

Characterization of the VeloPix Detector Gain Response to Fe-55 Irradiation

Student: Alfonso Puicercus

Supervisor: Kristof De Bruyn



university of
groningen

Nikhef



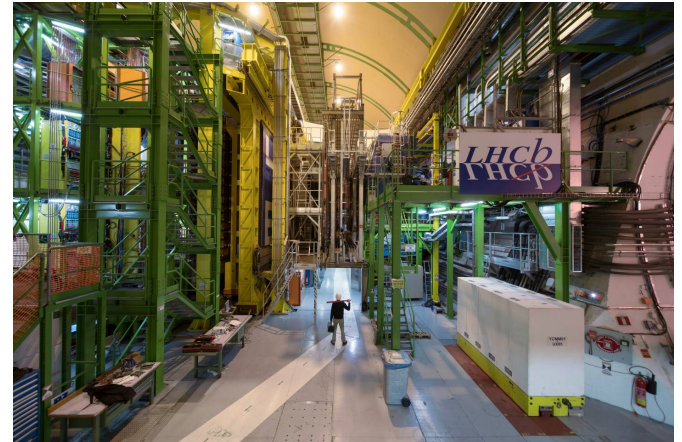
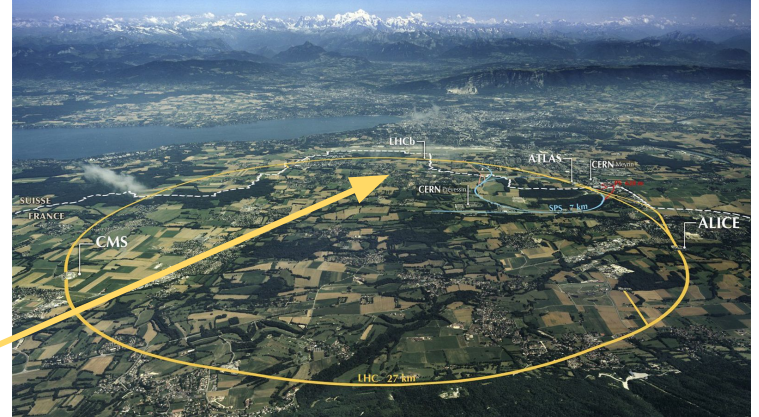
Introduction

Large Hadron Collider (LHC):
is the largest particle accelerator in the world

Various experiments, but among them LHCb

Improvement of measurements \Rightarrow Upgrade

Vertex Locator (VELO) detector upgraded!



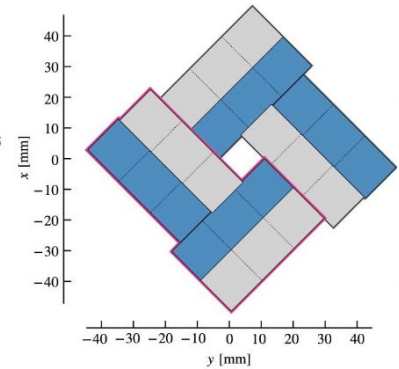
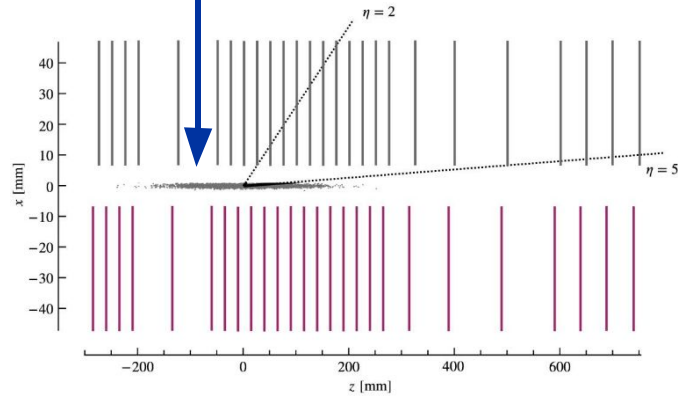
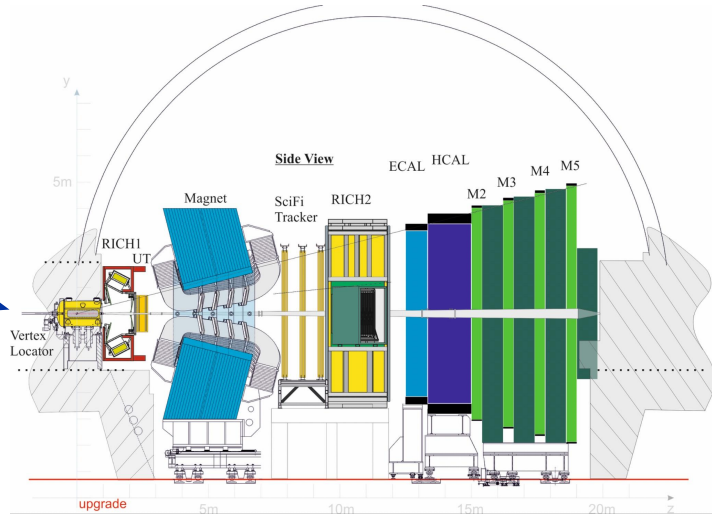
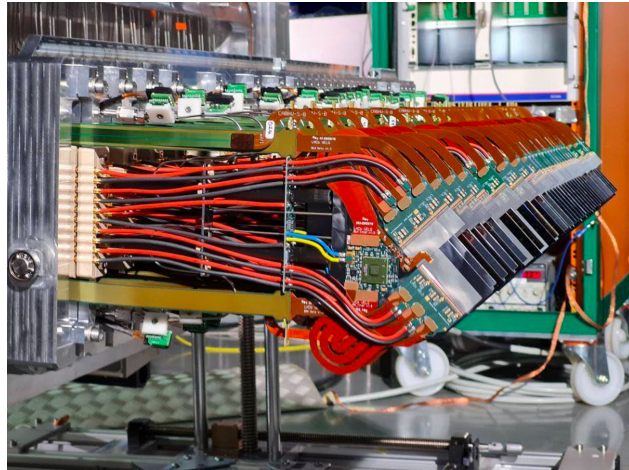
Vertex Locator (VELO)

First sub-detector particles encounter

Measures the ionising particles paths

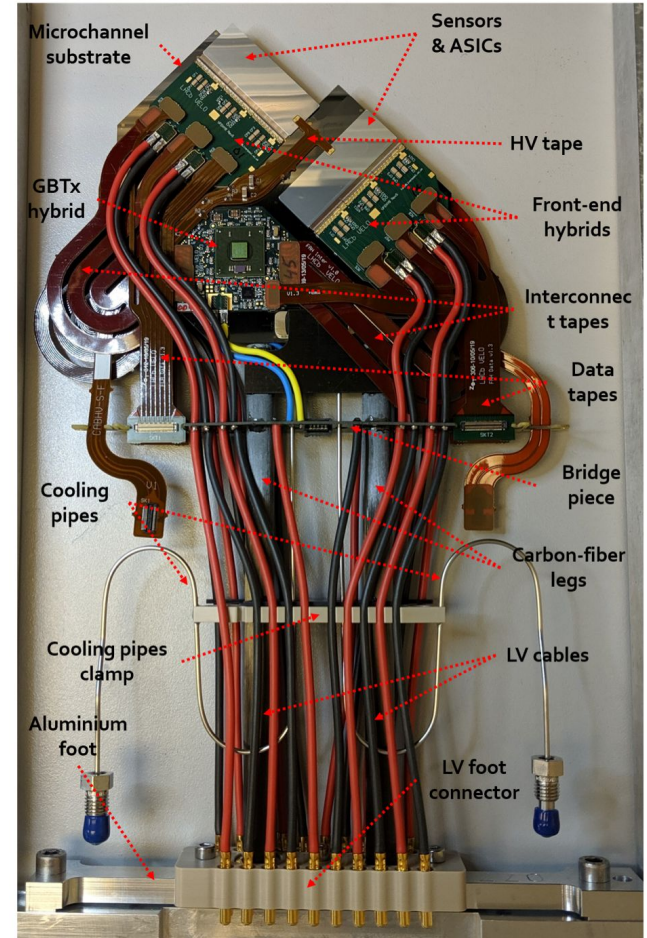
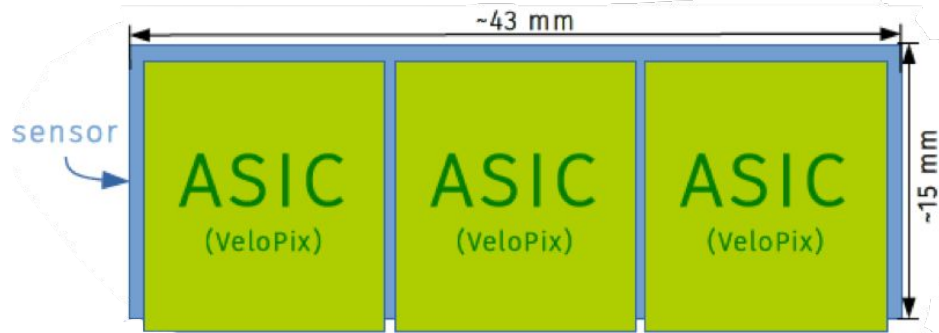
52 Modules along travelling direction

Surrounds pp interaction region



Vertex Locator (VELO)

One module = 4 sensors with 3 VeloPix ASICs each



Application-Specific Integrated Circuits (ASICs)
Digital to Analog Converter (DAC)

Velopix

ASIC

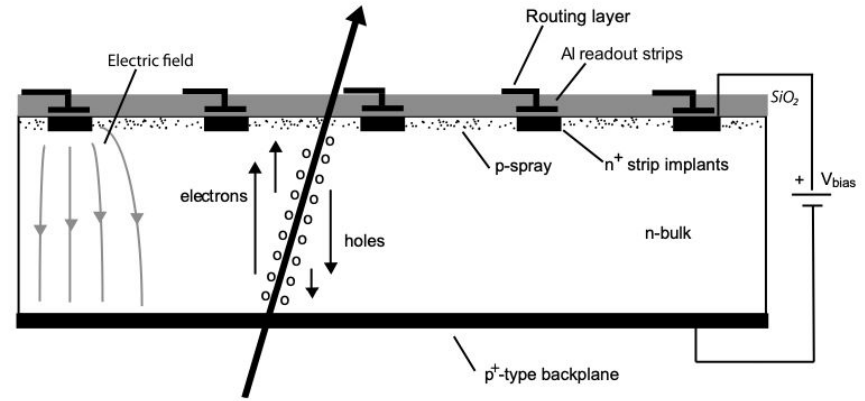
256x256 pixels/ASIC

200 μm n-on-p Silicon depletion zone

Detection Process:

- Creation of electron-hole pairs (ehp)
- Collect current
- Digital signal [DAC]

Application-Specific Integrated Circuits (ASICs)
Digital to Analog Converter (DAC)



ASIC Pixel Schematic with incident ionising particle

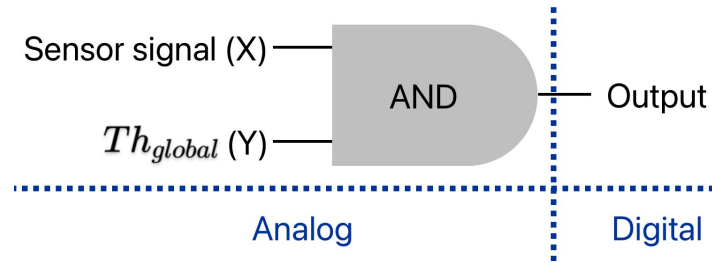
Signals, Noise and Thresholds

Threshold [DAC] : minimum signal amplitude required for a pixel to register a hit.

[DAC] = Unit used by ASICs. Associates a Digital value to an Analog voltage or current.

Global Threshold Th_{global} :

Discern between *noise* or *hit* from particle.



Digital to Analog Converter (DAC)

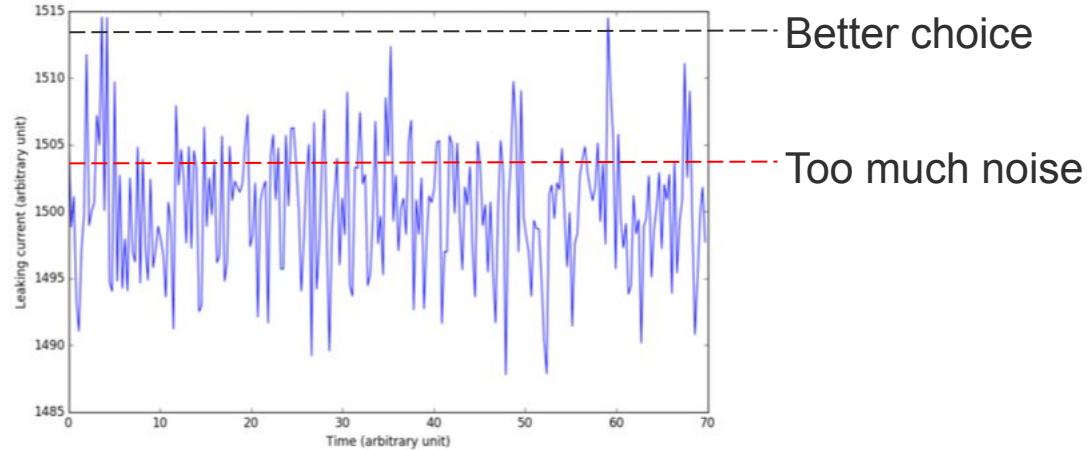


Figure 3: A simulation on the noise of a pixel.

Overview

Calibration and project goal:

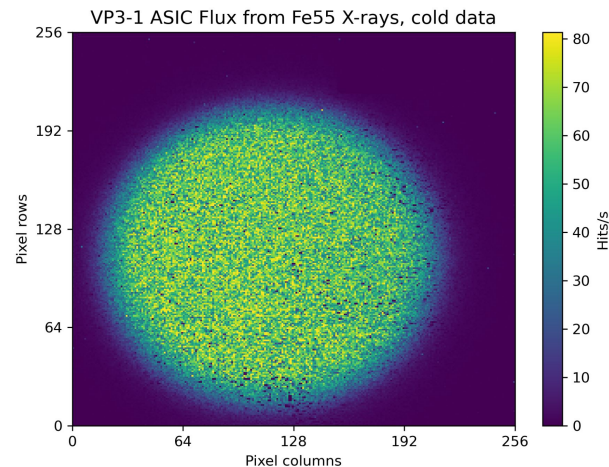
- Conversion factor or Gain, K [e-/DAC]

Controlled scenario with radiation source $\Rightarrow K$ [e-/DAC] for ASIC

- Compare to VeloPix ASIC design paper estimate

$$K_{est} \text{ [e-/DAC]} = 15.45 \pm 0.51$$

Application-Specific Integrated Circuits (ASICs)
Digital to Analog Converter (DAC)



Overview

Calibration goal:

- Conversion factor or Gain, K [e-/DAC]

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- Compare to VeloPix ASIC design paper estimate

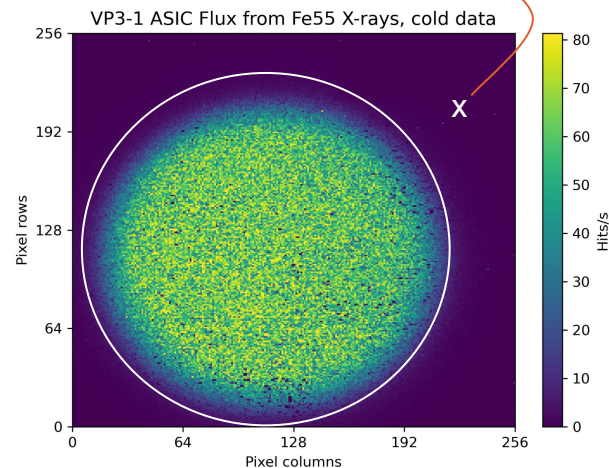
$$K_{est} \text{ [e-/DAC]} = 15.45 \pm 0.51$$

Other goals:

- Explore individual vs ASIC behaviour
- Explore possible biases

Application-Specific Integrated Circuits (ASICs)
Digital to Analog Converter (DAC)

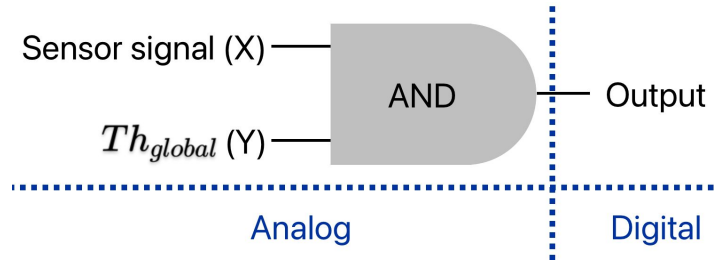
$$K \text{ [e-/DAC]} = x \pm \Delta x$$



Theory: Signals, Noise and Thresholds

Pixel-to-pixel variations exist \Rightarrow can be fixed with small configuration setting in pixels

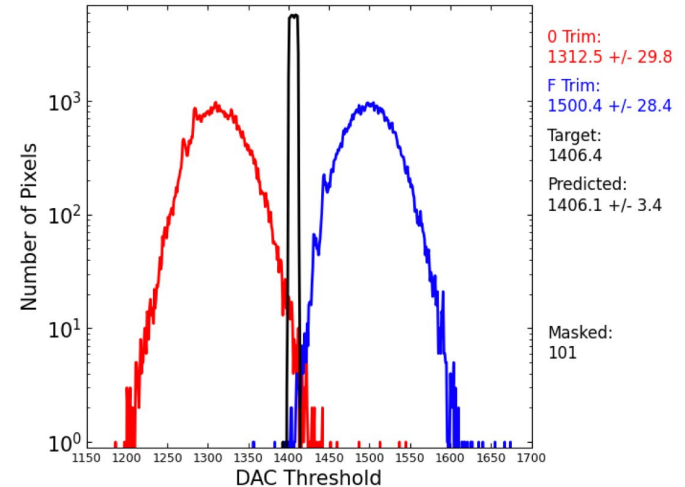
\Rightarrow Trim setting: Acts as current offset added to input signal



$$Hit_{detected} = Signal_{input} + Trim > Th_{global}$$

Equalisation process:

1. Best Trim setting matrix
2. Global threshold and noise baseline for ASIC
3. Masked pixel matrix



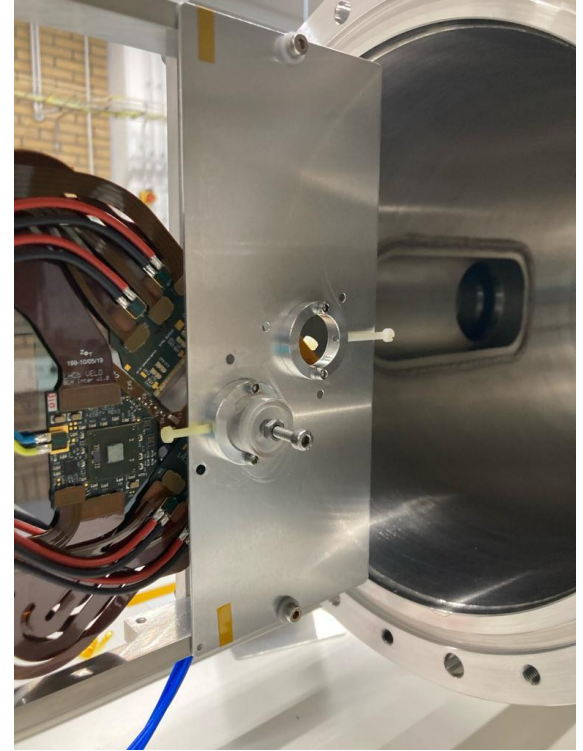
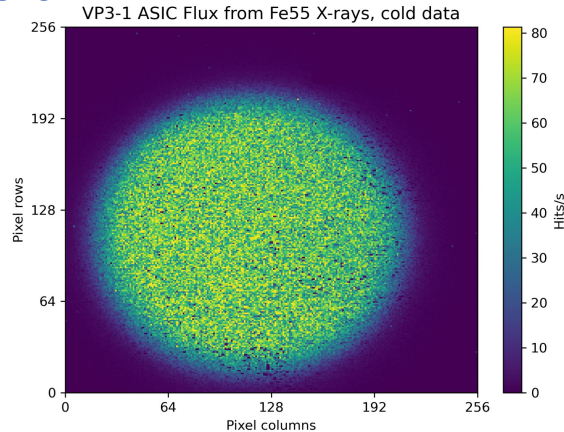
Theory: Signals, Noise and Thresholds

Fe55 source:

- 60% Auger e- with energy 5.19 keV, not measured
- 28% X-rays with energy 5.9 keV
- 12% other not relevant processes

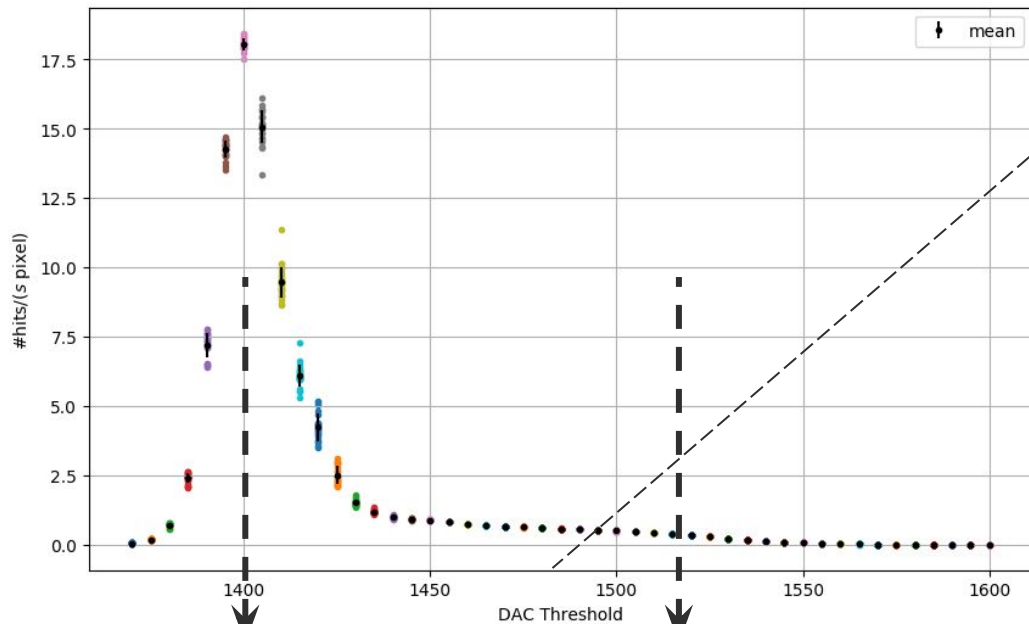
Only X-ray flux detected on ASIC

$$E_{\gamma} = 5.9\text{keV}$$

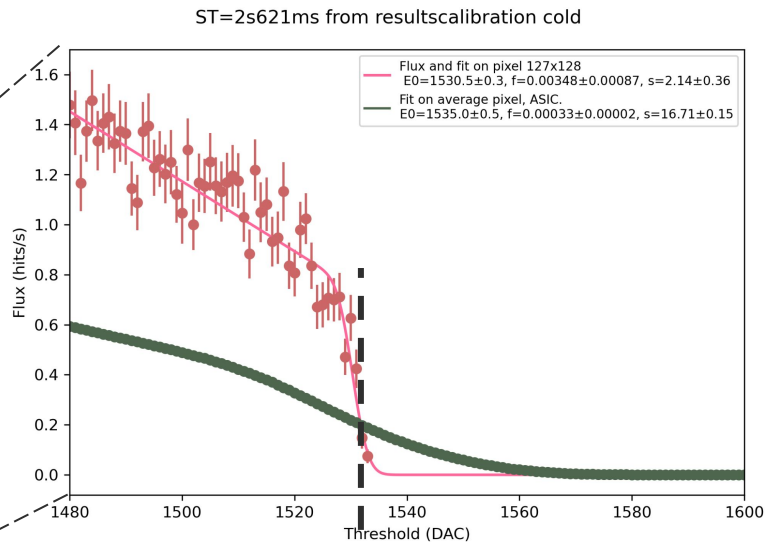


Theory: Signals, Noise and Thresholds

Flux vs Threshold scan



E_b E_0
 $target = E_0 - E_b$



Theory: Source and Detection

Processes:

1. Photoelectric effect, $E_g = 1.12\text{eV}$

$$E = E_\gamma - E_g \Rightarrow E \approx E_\gamma$$

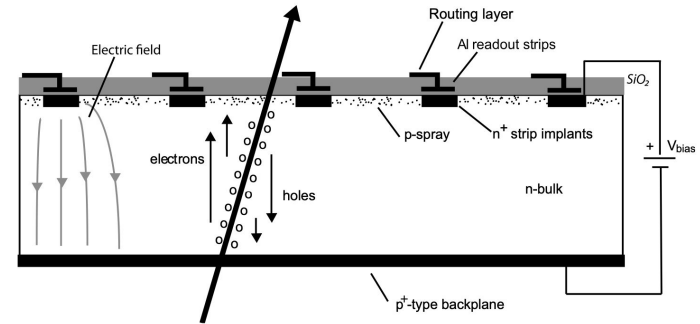
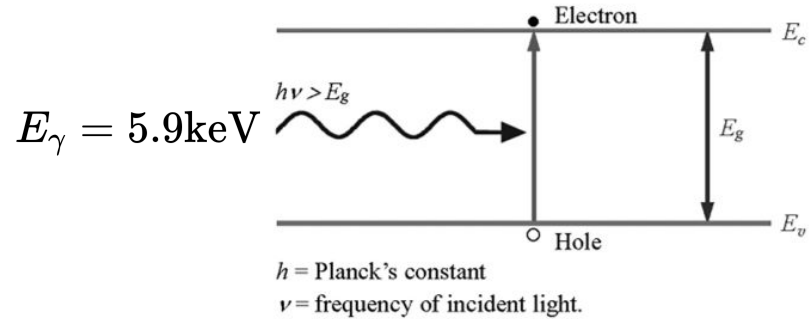
2. Average electron-hole pair-creation energy in Si: $E_{ehp} = 3.69 \pm 0.11 \text{ eV/ehp}$

$$\rightarrow n_{ehp} = \frac{E_\gamma}{E_{ehp}} = \frac{5900 \text{ eV}}{3.69 \text{ eV/ehp}} = 1598.92 \text{ ehp}$$

Energy deposition

$$\rightarrow target = E_0 - E_b, n_{ehp}$$

$$K \left[\frac{e^-}{DAC} \right] = \frac{n_{e^-}}{target} = \frac{E_\gamma}{E_{ehp}} \frac{1}{(E_0 - E_b)}$$



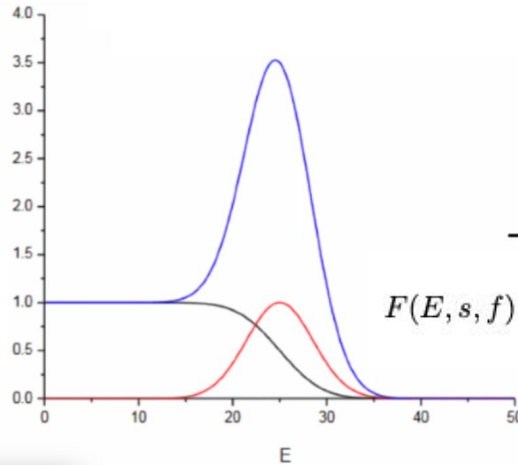
Theory: Flux Models

Flux model structure

- Blue: Signal 1 pixel $(1 - f) \cdot \frac{1}{s\sqrt{2\pi}} e^{-\frac{1}{2}\left(\frac{E-E_0}{s}\right)^2}$
 - Black: charge sharing $f \cdot \frac{1}{2} \operatorname{erfc}\left(\frac{E - E_0}{s}\right)$
- $f(E, s, f)$

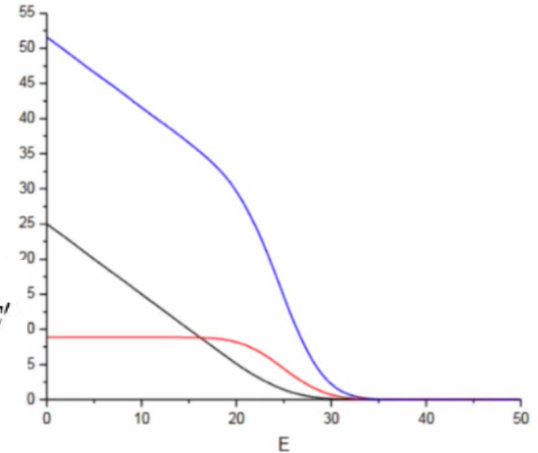
$$\operatorname{erfc}(x) = 1 - \frac{2}{\sqrt{\pi}} \int_0^x e^{-t^2} dt$$

Graph by MD Galati



Integrating from
our threshold E to
infinity

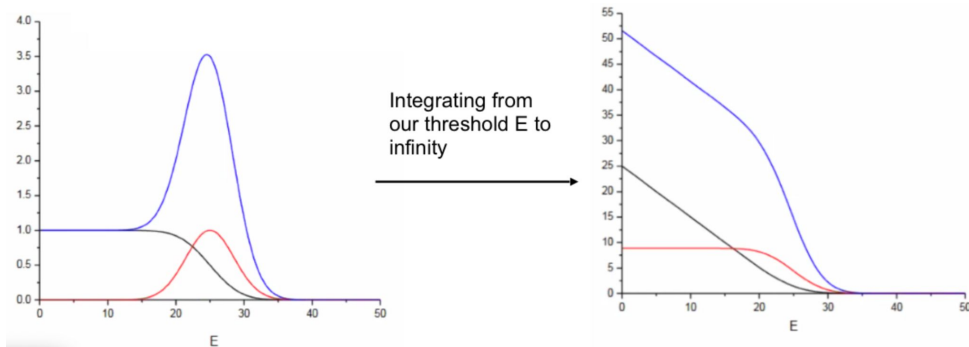
$$F(E, s, f) = \int_E^{\infty} f(E', s, f) dE'$$



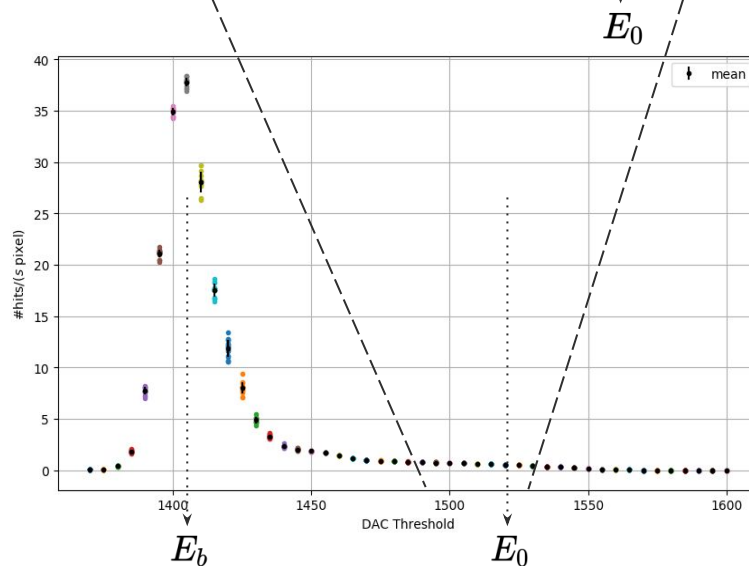
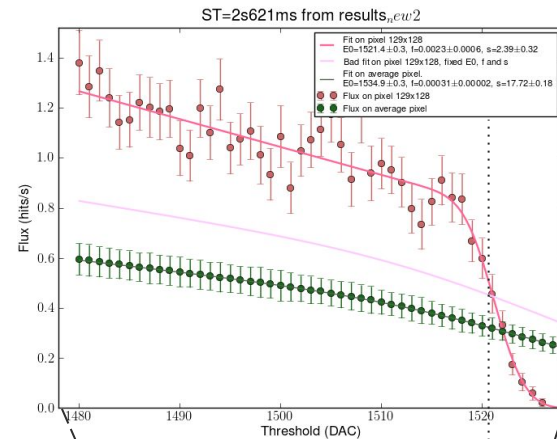
Theory: Flux Models

Flux model structure

$$F(E) = Af \cdot \frac{1}{2} \left(\frac{s}{\sqrt{\pi}} e^{-\left(\frac{E-E_0}{s}\right)^2} + (E_0 - E) \cdot \operatorname{erfc}\left(\frac{E - E_0}{s}\right) \right) + A(1 - f) \cdot \frac{1}{s\sqrt{8\pi}} \cdot \operatorname{erfc}\left(\frac{E - E_0}{s\sqrt{2}}\right)$$



Graph by MD Galati

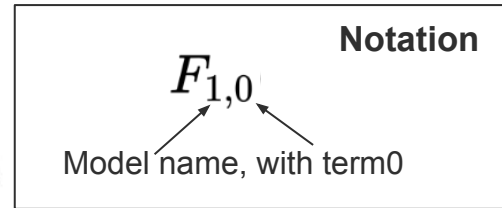


Theory: Flux Models

Other possibilities:

$$F_{1,0}(E) = Af \cdot \frac{1}{2} \left(\frac{s}{\sqrt{\pi}} e^{-\left(\frac{E-E0}{s}\right)^2} + (E0 - E) \cdot \operatorname{erfc}\left(\frac{E - E0}{s}\right) \right) + A(1 - f) \cdot \frac{1}{s\sqrt{8\pi}} \cdot \operatorname{erfc}\left(\frac{E - E0}{s\sqrt{2}}\right)$$

$$F_1(E) = Af \cdot \frac{1}{2} (E0 - E) \cdot \operatorname{erfc}\left(\frac{E - E0}{s}\right) + A(1 - f) \cdot \frac{1}{s\sqrt{8\pi}} \cdot \operatorname{erfc}\left(\frac{E - E0}{s\sqrt{2}}\right)$$



Using a different parametrization: *AB model* $A^* = \frac{1}{2}fA$, $B^* = \frac{1}{2}(1 - f)A$

$$F_{AB,0}(E) = A^* \cdot \left(\frac{s}{\sqrt{\pi}} e^{-\left(\frac{E-E0}{s}\right)^2} + (E0 - E) \cdot \operatorname{erfc}\left(\frac{E-E0}{s}\right) \right) + B^* \cdot \frac{1}{s\sqrt{2\pi}} \cdot \operatorname{erfc}\left(\frac{E-E0}{s\sqrt{2}}\right)$$

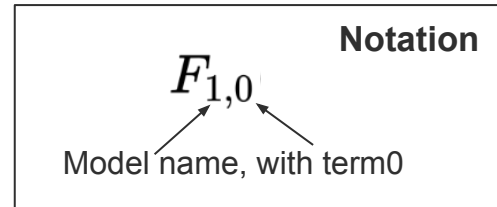
$$F_{AB}(E) = A^* \cdot (E0 - E) \operatorname{erfc}\left(\frac{E-E0}{s}\right) + B^* \cdot \frac{1}{s\sqrt{2\pi}} \cdot \operatorname{erfc}\left(\frac{E-E0}{s\sqrt{2}}\right)$$

Theory: Flux Models

Other possibilities:

$$F_{1,0}(E) = Af \cdot \frac{1}{2} \left(\frac{s}{\sqrt{\pi}} e^{-\left(\frac{E-E0}{s}\right)^2} + (E0 - E) \cdot \operatorname{erfc}\left(\frac{E - E0}{s}\right) \right) + A(1 - f) \cdot \frac{1}{s\sqrt{8\pi}} \cdot \operatorname{erfc}\left(\frac{E - E0}{s\sqrt{2}}\right)$$

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Using various s parameters: 2s model

$$F_{2s,0}(E) = Af \cdot \frac{1}{2} \left(\frac{s_1}{\sqrt{\pi}} e^{-\left(\frac{E-E0}{s_1}\right)^2} + (E0 - E) \cdot \operatorname{erfc}\left(\frac{E-E0}{s_1}\right) \right) + A(1 - f) \cdot \frac{1}{s_2\sqrt{8\pi}} \cdot \operatorname{erfc}\left(\frac{E-E0}{s_2\sqrt{2}}\right)$$

$$F_{2s}(E) = \frac{1}{2} fA \cdot (E0 - E) \operatorname{erfc}\left(\frac{E-E0}{s_1}\right) + \frac{1}{2} (1 - f)A \cdot \frac{1}{s_2\sqrt{2\pi}} \cdot \operatorname{erfc}\left(\frac{E-E0}{s_2\sqrt{2}}\right)$$

$$F_{2s,AB}(E) = A^* \cdot (E0 - E) \cdot \operatorname{erfc}\left(\frac{E-E0}{s_1}\right) + B^* \cdot \frac{1}{s_2\sqrt{2\pi}} \cdot \operatorname{erfc}\left(\frac{E-E0}{s_2\sqrt{2}}\right)$$

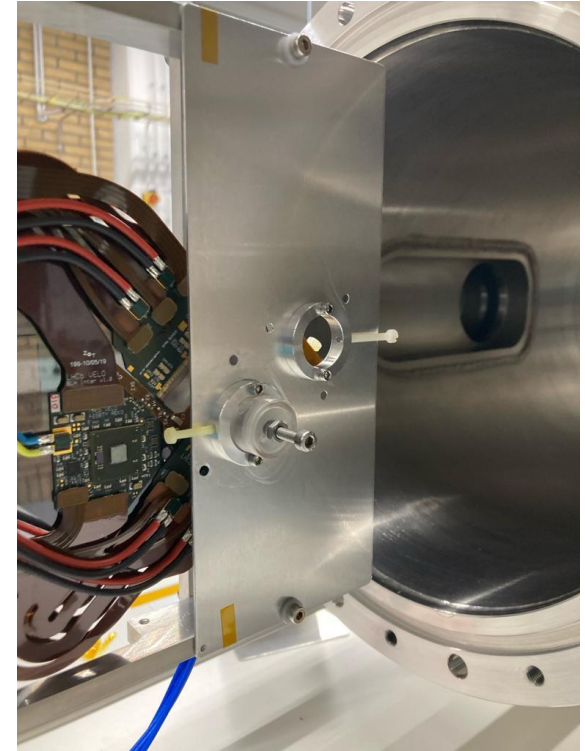
Data and other specifics

Setup:

- Module at Nikhef for testing
- Cooling system used for data taking

Some data specifics:

- Two module temperatures, with same distance
- “Module production” equalisation
- MiniDAQ2 (data acquisition equipment)



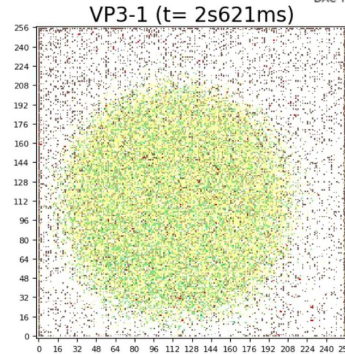
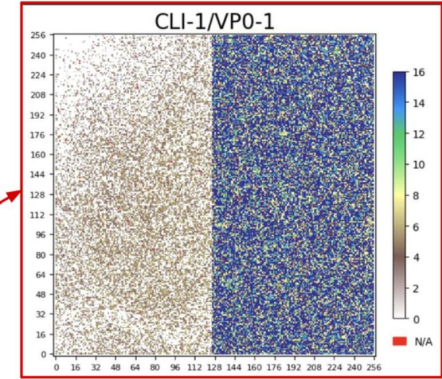
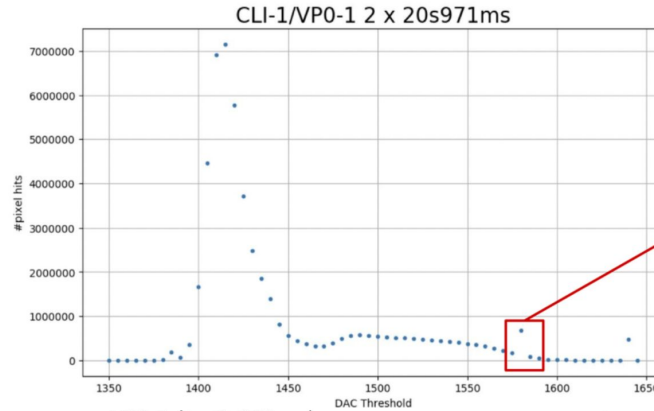
Set	Label	Module Temp.	ASIC	ST	nacq	Thr _{min}	Thr _{max}	Thr _{step}	Total time (h)
1	Cold	-20°C	VP3-1	2 s621 ms	50	1480	1600	1	4.36
2	Warm	20°C	VP3-1	2 s621 ms	100	1480	1600	1	8.73

Data and other specifics

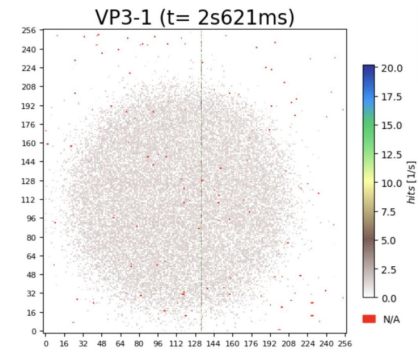
Filtering:

Anomalies are removed.

Acquisitions that are empty or considered bad



thr=1494, acq=18



thr=1527, acq=78

Data and other specifics

Fitting and Pixel Categorisation:

Good: fit found and $\chi^2 < \chi_c^2$

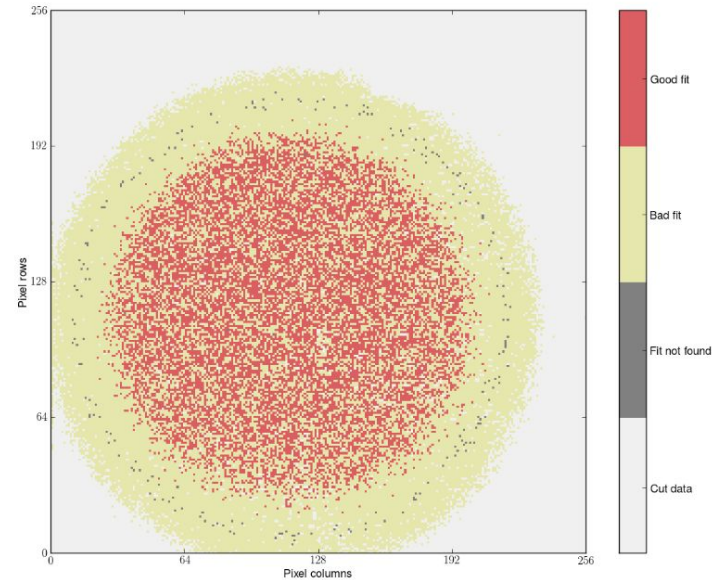
Bad: fit found but $\chi^2 > \chi_c^2$ or unphysical parameters

Fit not found: not converging

Cut data: no enough data, faulty or masked

$$\chi^2 = \sum_i \left(\frac{O_i - F_i}{U_i} \right)^2,$$

χ_c^2 with $\alpha = 0.05$ and dof = $n - 4$



Cold

Data and other specifics

Average behaviour of pixels:

- **Mean**
- **ASIC**
 - *Represents the average flux on the whole ASIC.*
 - *Takes into account bad fit pixels → not an accurate representation?*
- **ASICgood**
 - *Uses only good fit pixels → probably less biased*

Throughout analysis looking at:

Distributions + Mean, ASIC & ASICgood

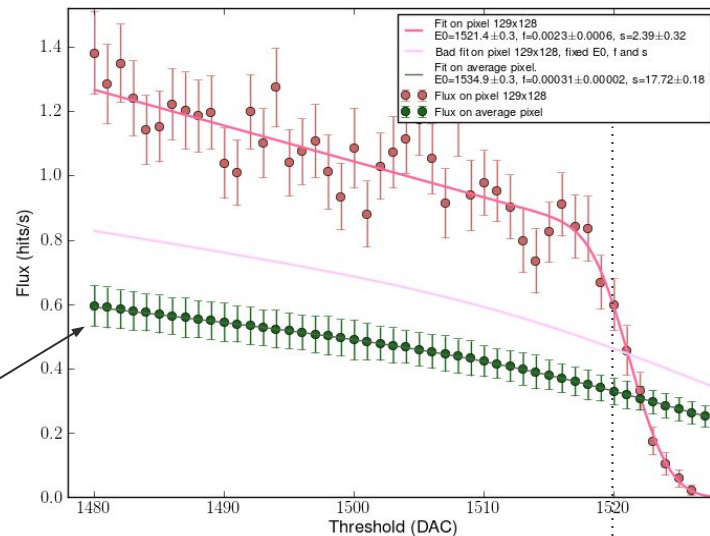
Can we say anything about the individual pixels from looking at the ASIC flux?

Analysis

Fit the data to the Flux equation allows us to:

$$F(E) = Af \cdot \frac{1}{2} \left(\frac{s}{\sqrt{\pi}} e^{-\left(\frac{E-E_0}{s}\right)^2} + (E_0 - E) \cdot \operatorname{erfc}\left(\frac{E - E_0}{s}\right) \right) + A(1 - f) \cdot \frac{1}{s\sqrt{8\pi}} \cdot \operatorname{erfc}\left(\frac{E - E_0}{s\sqrt{2}}\right)$$

- Categorise pixels
- Obtain physical parameters: E_0
- Target and gain $K[e-/DAC]$



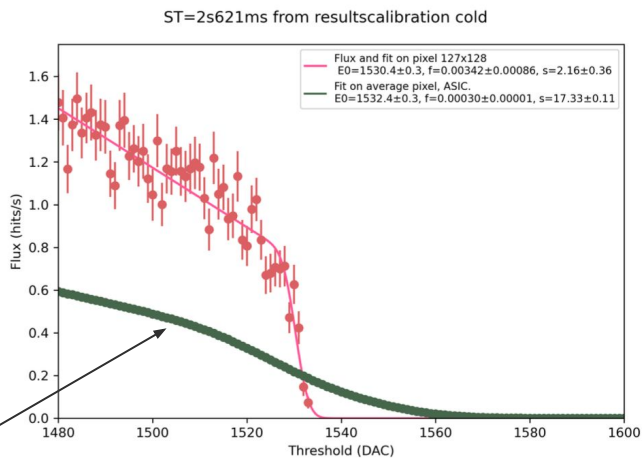
ASIC / average

E_0

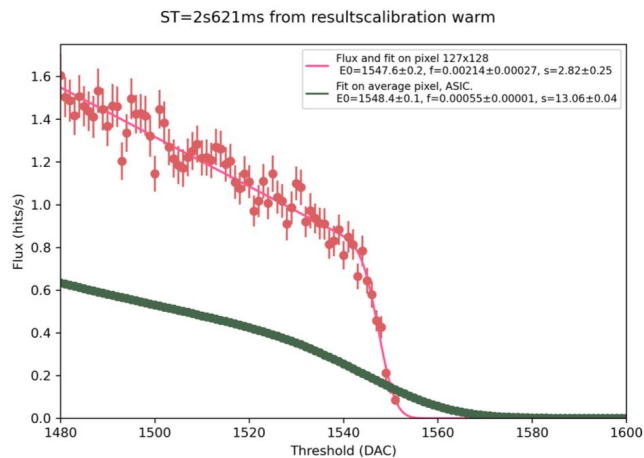
Analysis: Flux

Individual vs Average/ASIC

ASIC /
average



(a) Flux over threshold from the cold dataset.



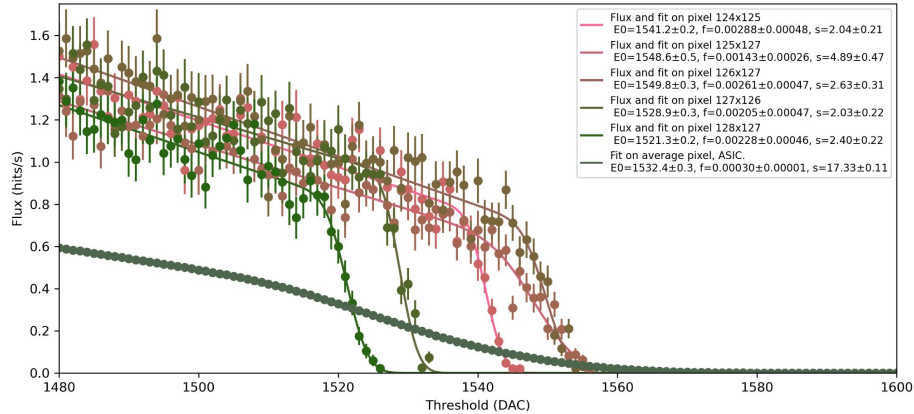
(b) Flux over threshold from the warm dataset.

Figure 9: Average and individual pixel 127 x 128 flux comparison for both the cold and warm dataset. The pink data points and line correspond to the individual pixel and the green data points and line to the average/ASIC flux.

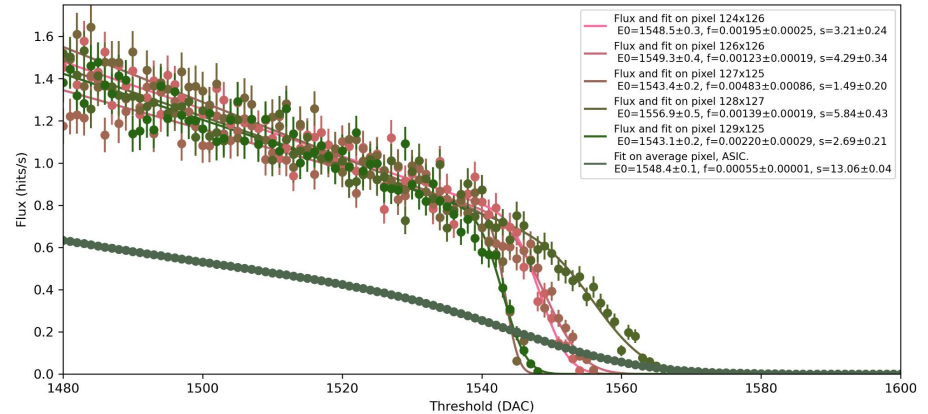
Analysis: Flux

Individual vs Average/ASIC

ST=2s621ms from resultscalibration cold



ST=2s621ms from resultscalibration warm

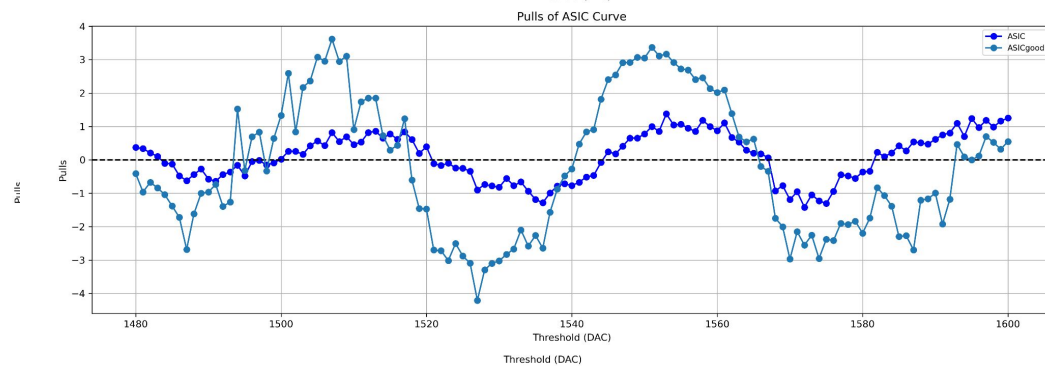
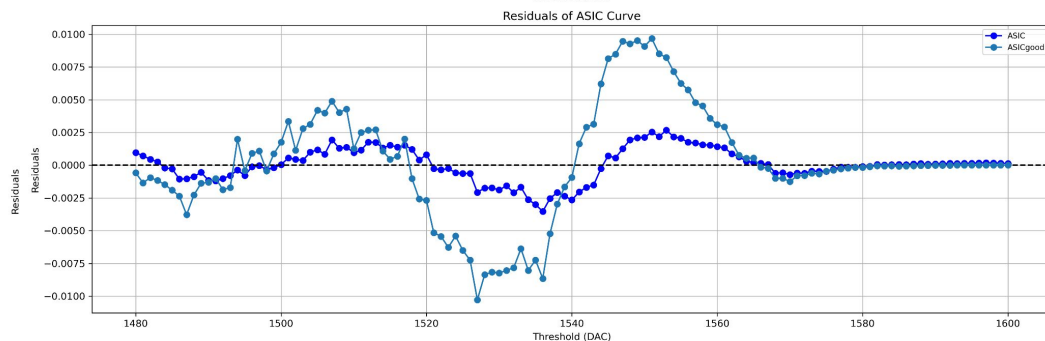
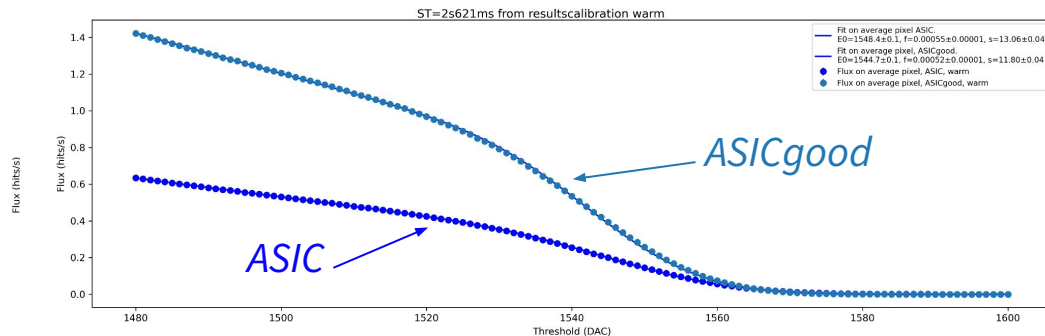


Analysis: Fitting

Individual vs Average/ASIC

Best flux model used here: $F_{1,0}$

$$p_{thr} = \frac{r_{thr}}{\Delta F_{raw,thr}} = \frac{F_{raw,thr} - F_{fit,thr}}{\Delta F_{raw,thr}}$$

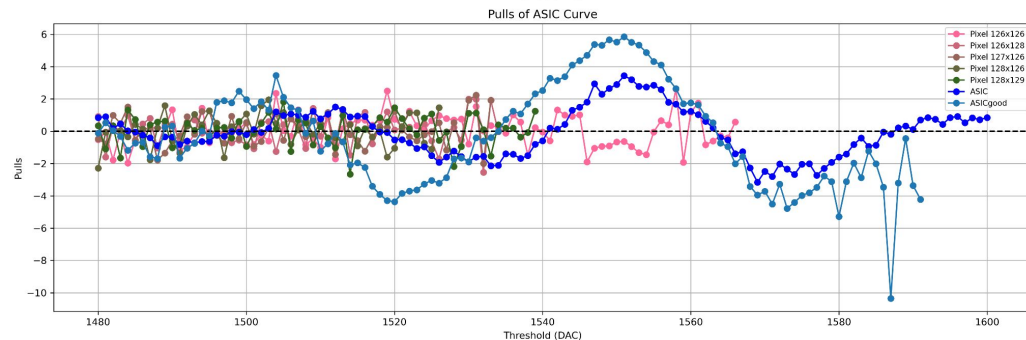
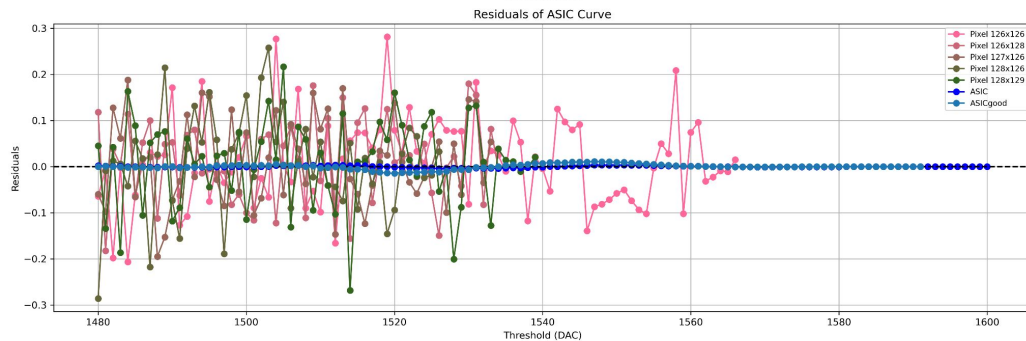
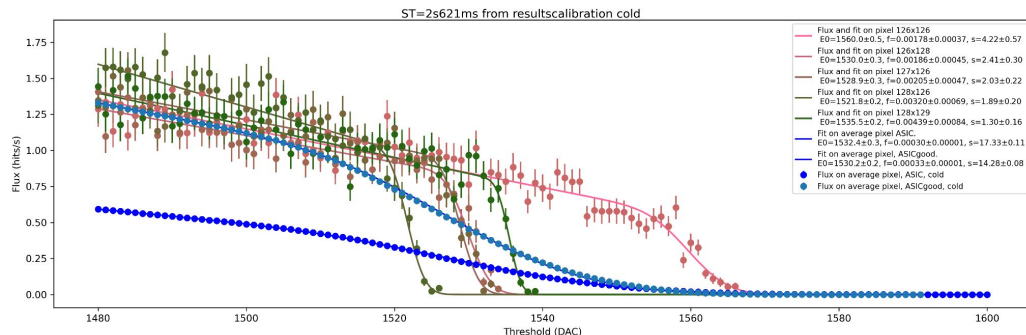


Analysis: Fitting

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Analysis: Fitting

Individual vs Average/ASIC

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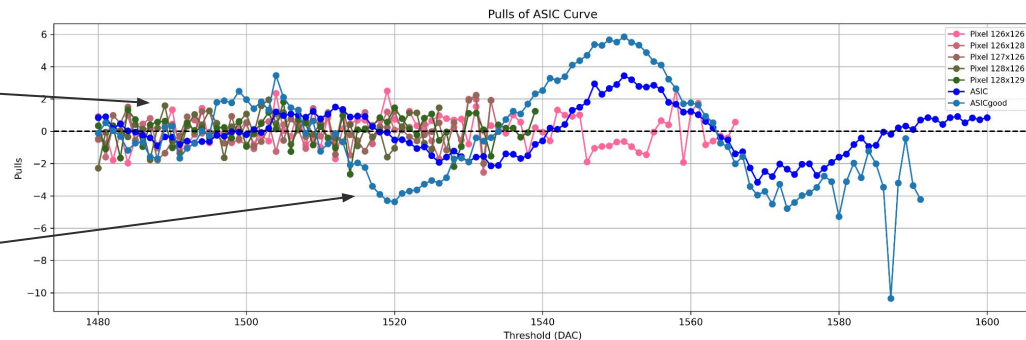
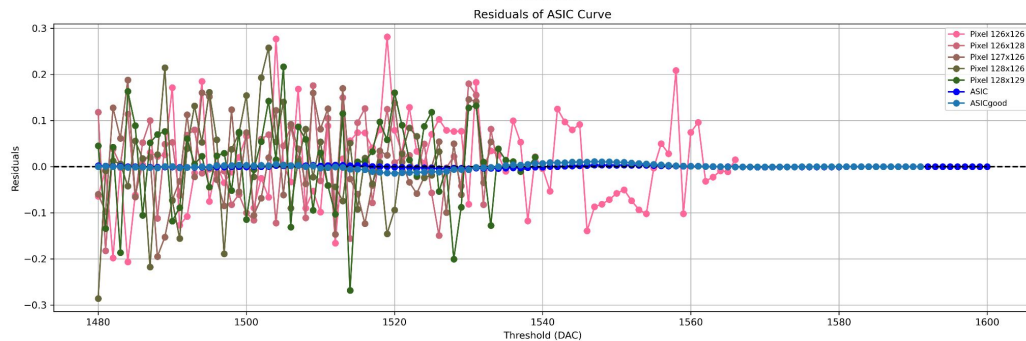
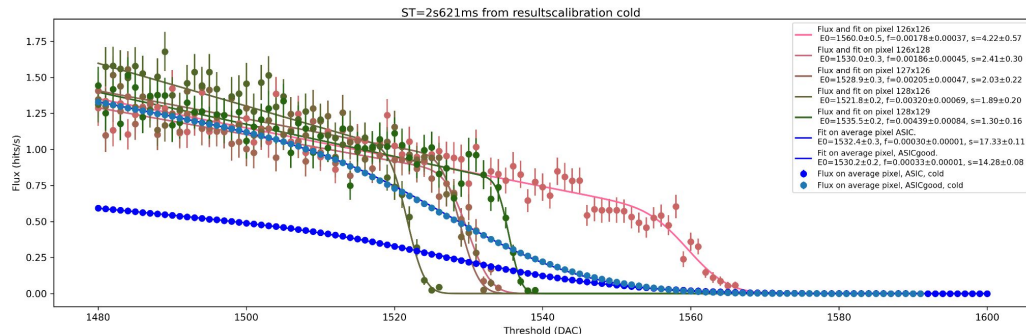
$$p_{thr} = \frac{r_{thr}}{\Delta F_{raw,thr}} = \frac{F_{raw,thr} - F_{fit,thr}}{\Delta F_{raw,thr}}$$

Pixels:

Fits are still acceptable

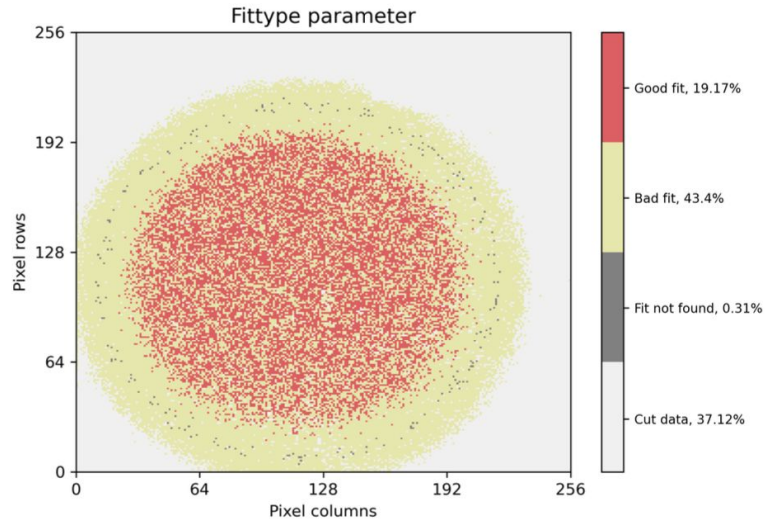
ASIC:

Regions with clear fitting issues

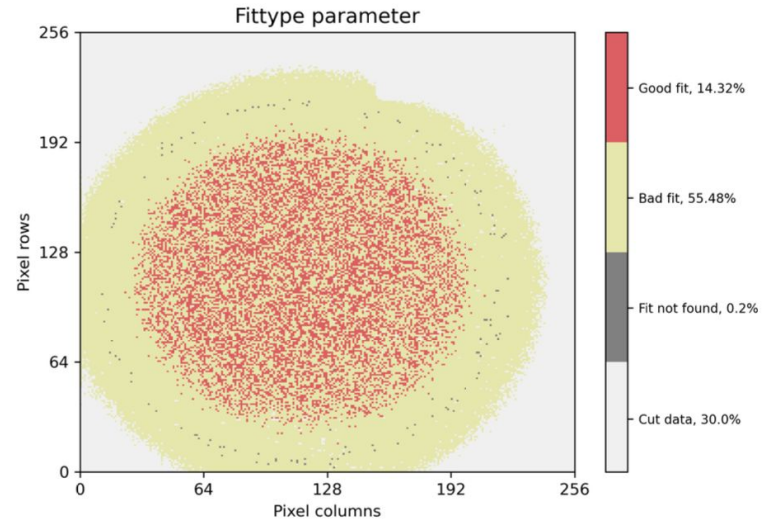


Analysis: Fitting

Pixel Categorisation



(a) Cold dataset.

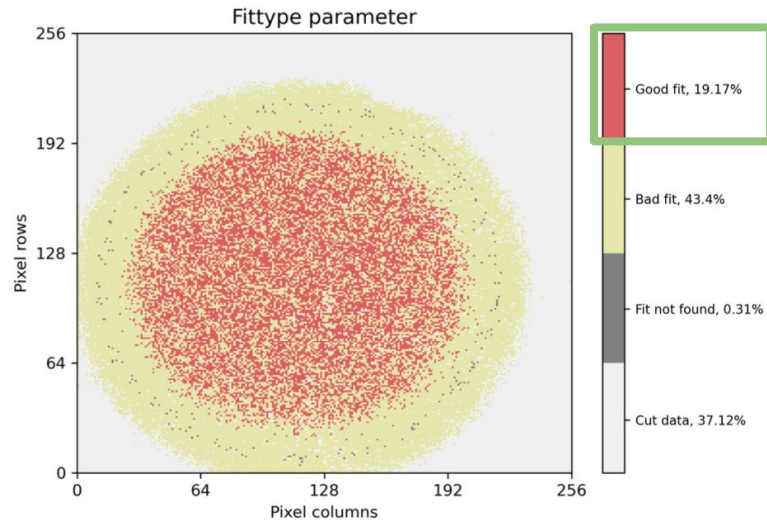


(b) Warm dataset.

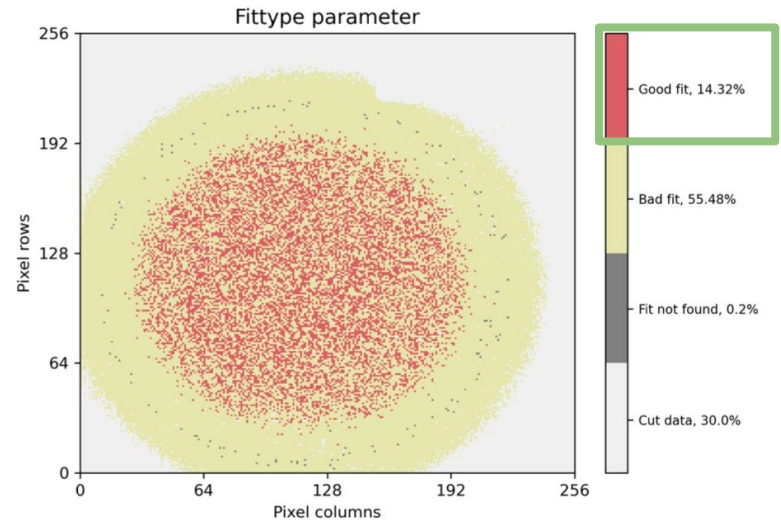
Figure 13: Heatmaps showing fit type category given to the individual pixels for the *cold* and *warm* dataset.

Analysis: Fitting

Pixel Categorisation



(a) Cold dataset.

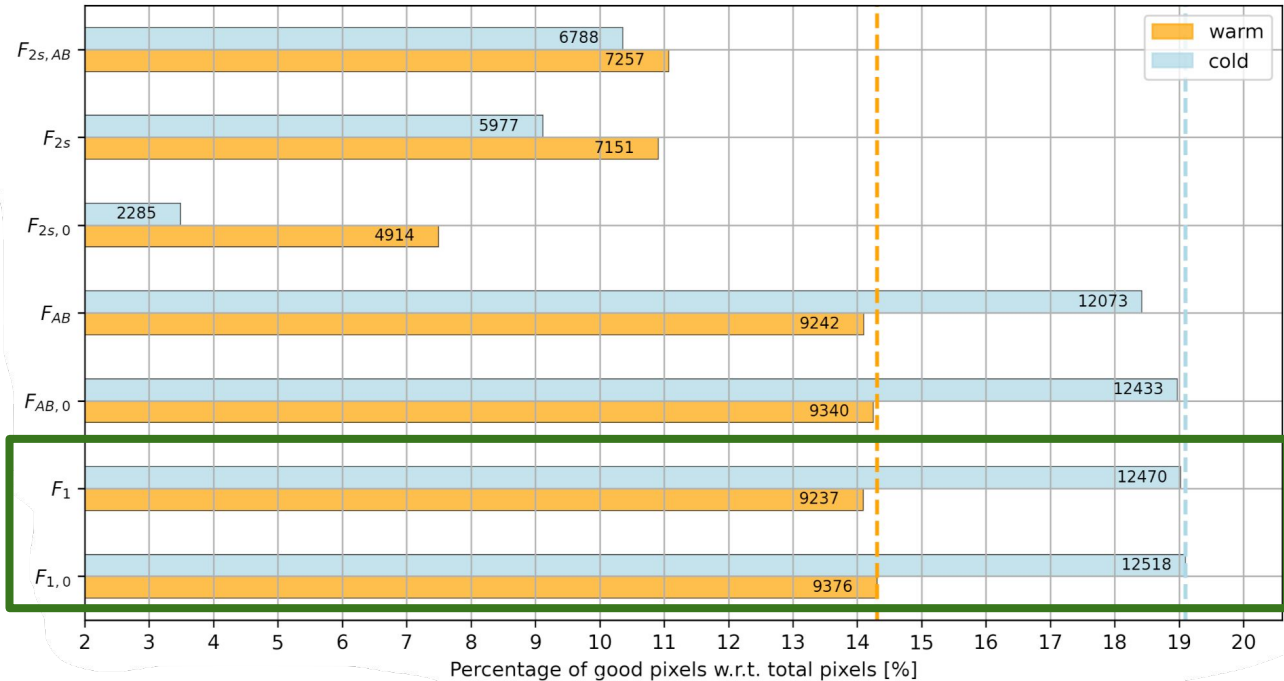


(b) Warm dataset.

Figure 13: Heatmaps showing fit type category given to the individual pixels for the *cold* and *warm* dataset.

Analysis: Fitting

Testing other flux models



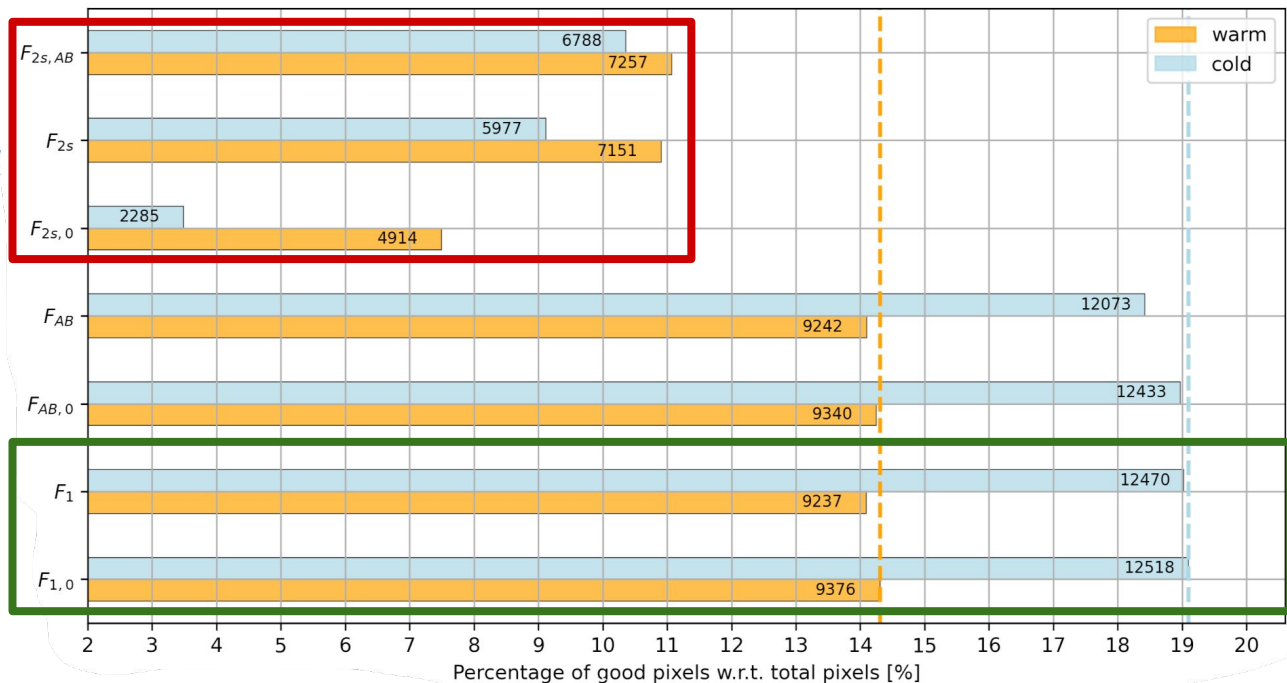
Main model used

Analysis: Fitting

Testing other flux models

2s model:

It does not fit well



Main model used

Analysis: Fitting

Testing other flux models

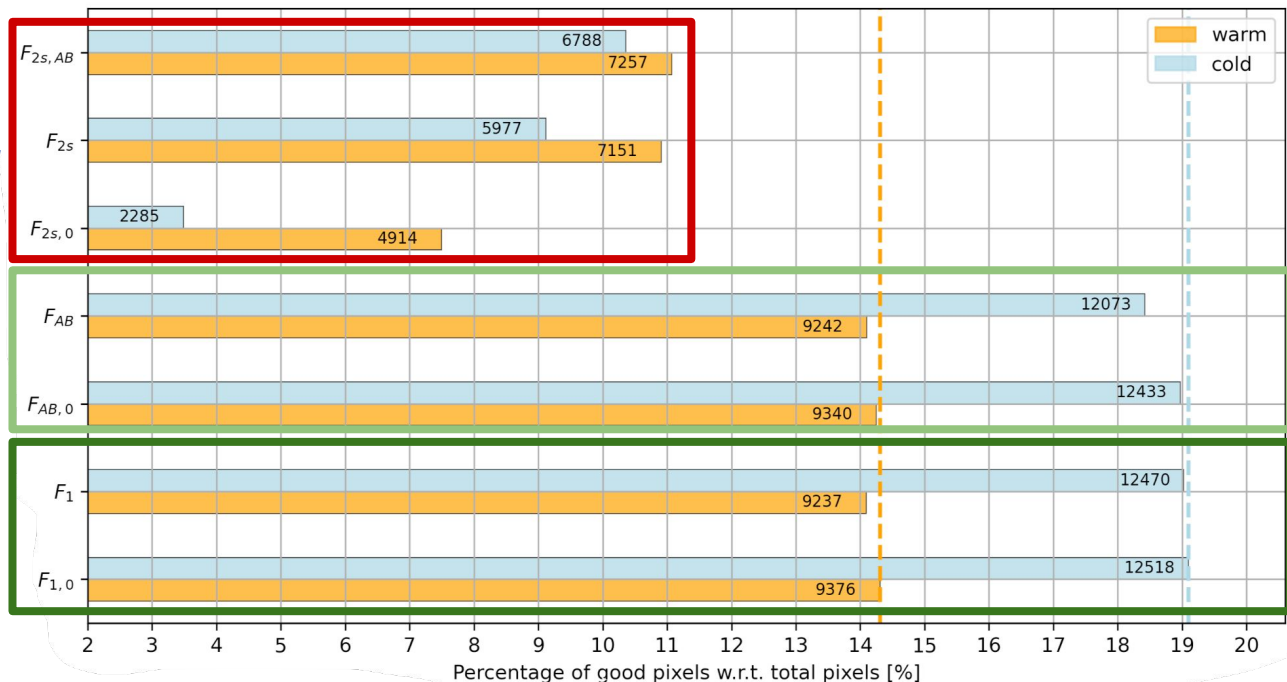
2s model:

It does not fit well

AB model:

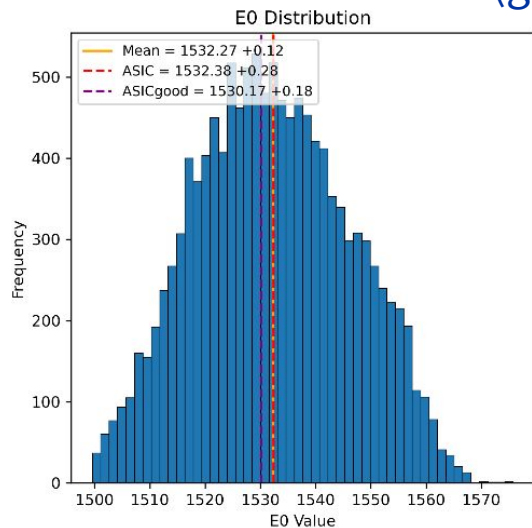
Equivalent to

Main model used

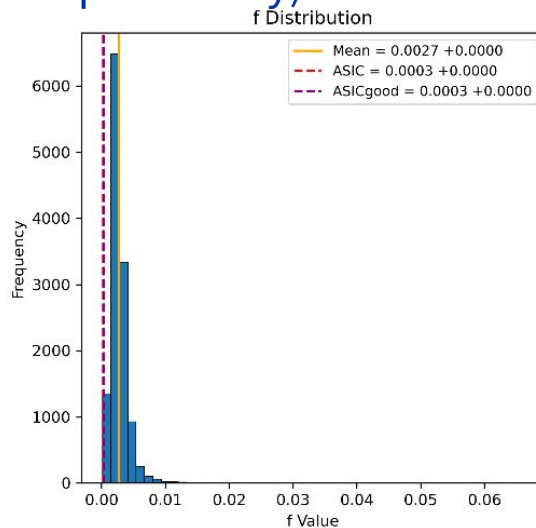


Analysis: Parameters

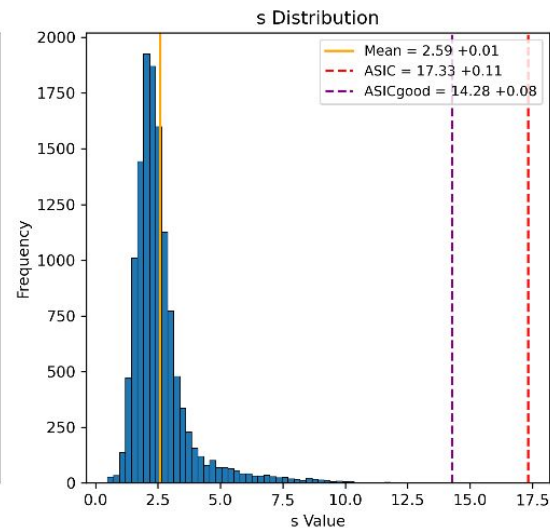
Parameter distributions (good pixels only)



E0: Threshold of flux drop



f: Charge sharing fraction

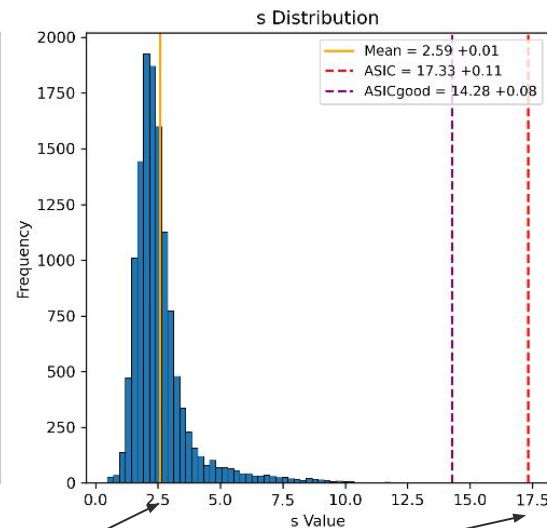
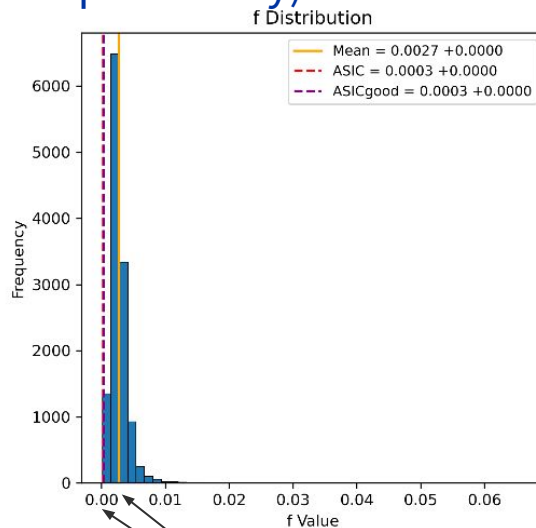
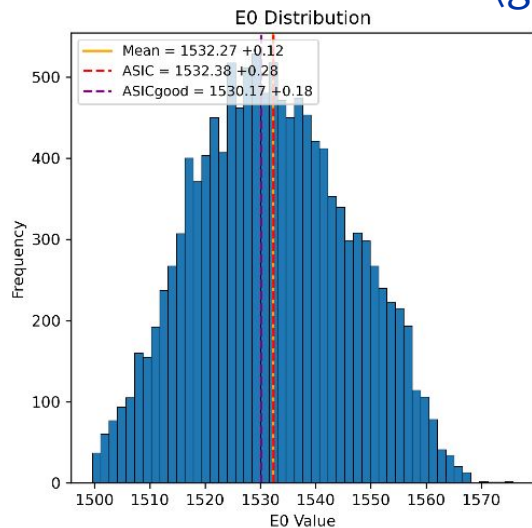


s: Spread around *E0*,
Sharpness of flux drop

Cold

Analysis: Parameters

Parameter distributions (good pixels only)



Cold



Difference between individual vs ASIC \Rightarrow Is ASIC value a good choice?

Analysis: Target

We know that:

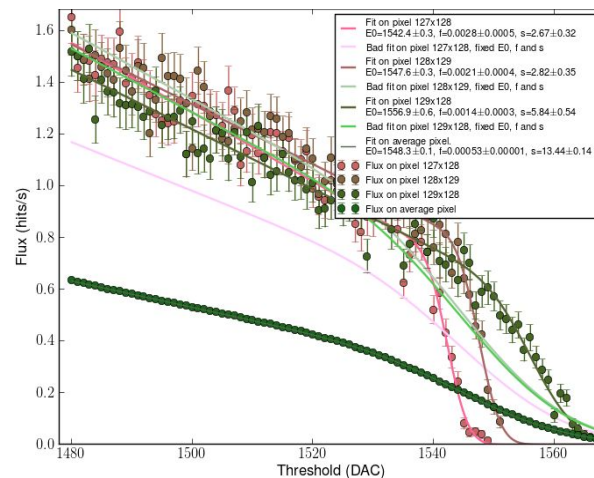
All pixels should agree on the energy deposition

Shift in E_0 due to pixel variations

We can use $target = E_0 - E_b$ to:

- Correct for pixel-to-pixel variations
- Obtain energy deposition

Cold



Analysis: Target

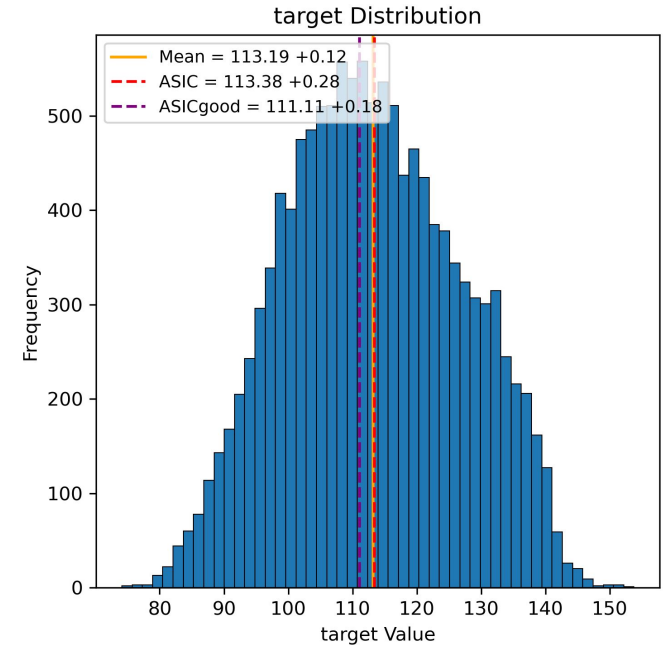
Calculation of $target = E_0 - E_b \rightarrow$ need E_b

Individual pixel values

- E_b using the best prediction from equalisation

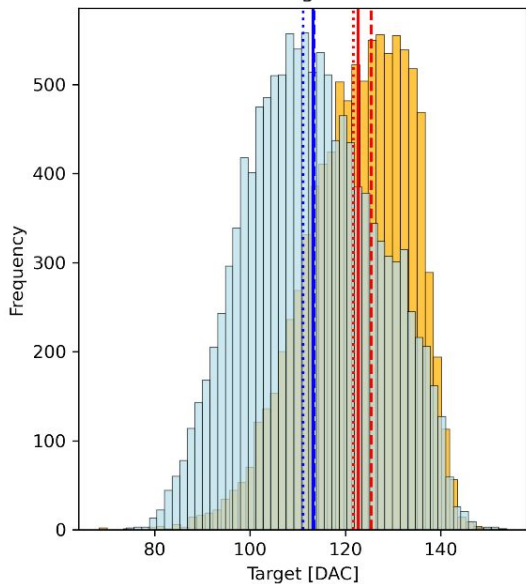
ASIC and ASICgood

- $E_{bASIC} = \overline{E_b}$, $target_{ASIC} = E_{0ASIC} - E_{bASIC}$



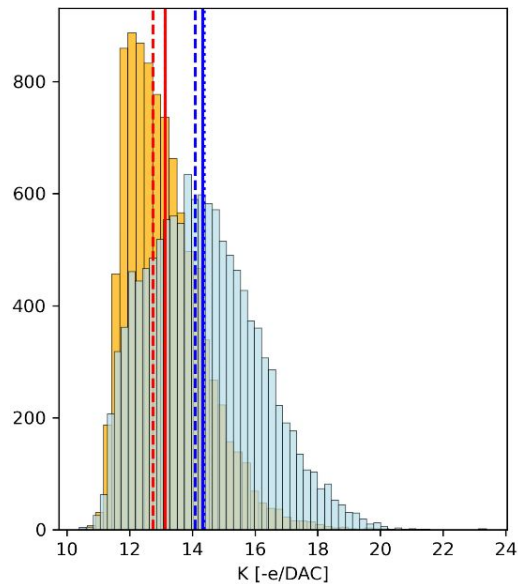
Analysis: Target and e-/DAC

Target



- warm , skewness: -0.54, kurtosis: 0.09
- Mean = 122.70 +- 10.86
- ASIC = 125.43 +- 0.08
- ASICgood = 121.72 +- 0.08
- cold , skewness: 0.07, kurtosis: -0.63
- Mean = 113.19 +- 13.58
- ASIC = 113.38 +- 0.28
- ASICgood = 111.11 +- 0.18

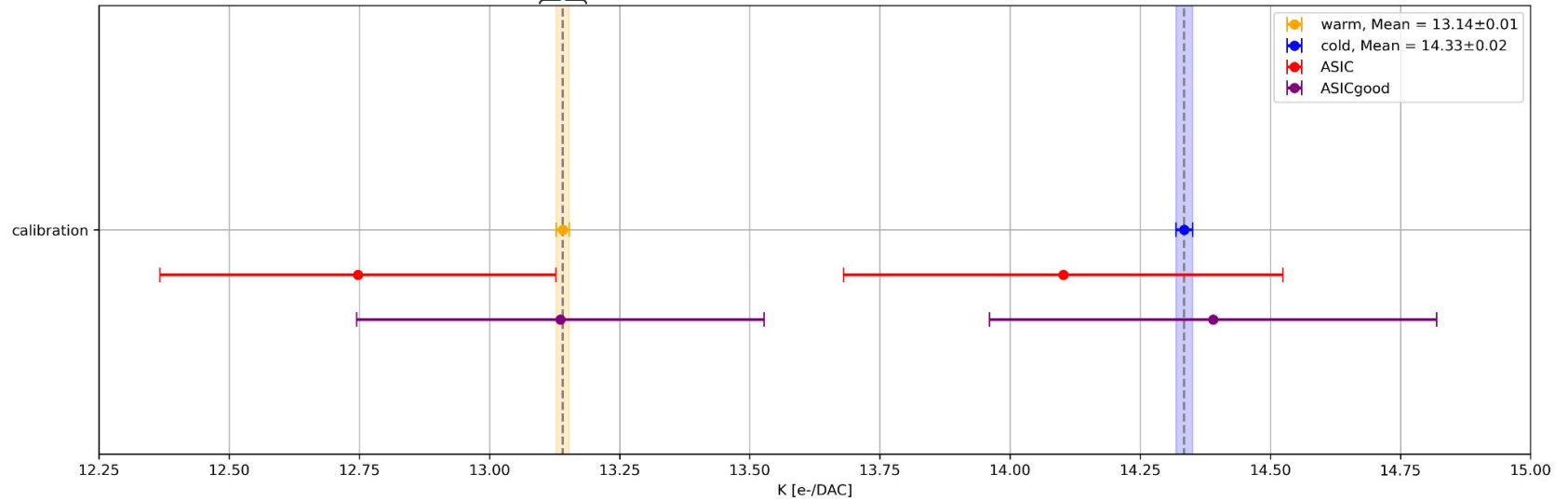
Distributions for calibration_baseline eDAC



- warm , skewness: 1.18, kurtosis: 2.59
- Mean = 13.14 +- 1.26
- ASIC = 12.75 +- 0.38
- ASICgood = 13.14 +- 0.39
- cold , skewness: 0.45, kurtosis: -0.19
- Mean = 14.33 +- 1.76
- ASIC = 14.10 +- 0.42
- ASICgood = 14.39 +- 0.43

Analysis: Gain K [e-/DAC]

Mean gain and uncertainty $SEM = \sigma/\sqrt{n}$



Systematic uncertainties and biases

Exposure time influence

Warm dataset has twice as much exposure time

Set	Label	Module Temp.	ASIC	ST	nacq	Thr _{min}	Thr _{max}	Thr _{step}	Total time (h)
1	Cold	-20°C	VP3-1	2 s621 ms	50	1480	1600	1	4.36
2	Warm	20°C	VP3-1	2 s621 ms	100	1480	1600	1	8.73

New dataset variations with equal exposure time on both *warm* and *cold*:

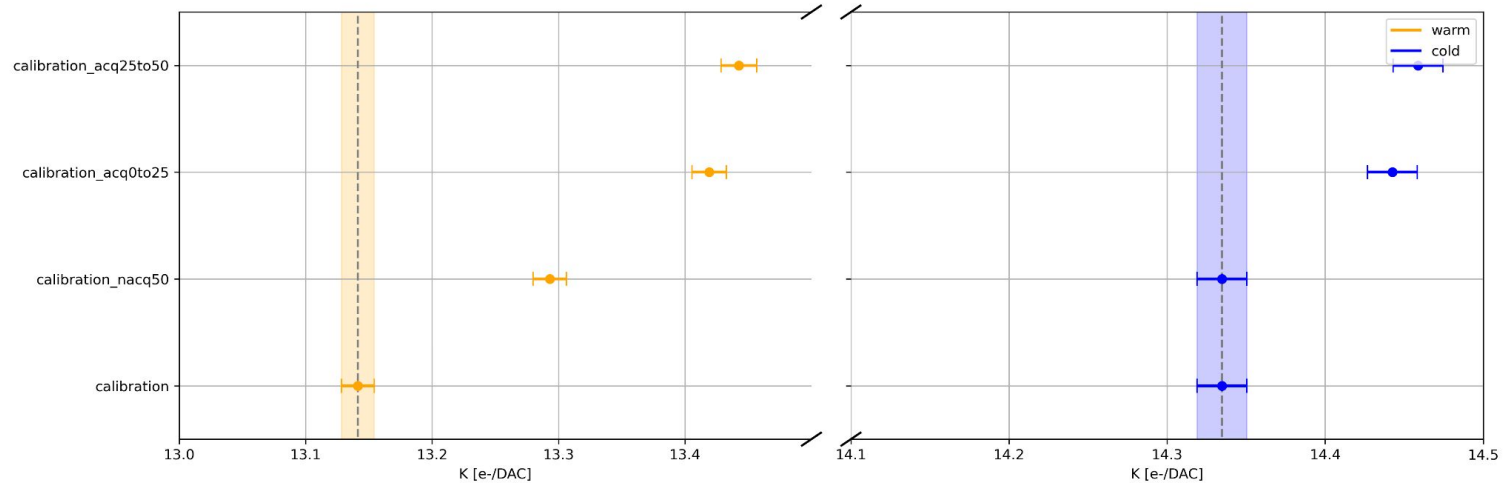
calibration_nacq50: using acquisitions in the [0,50] range.

calibration_acq0to25: acqs in [0,25] range

calibration_acq25to50: acqs in [25,50] range

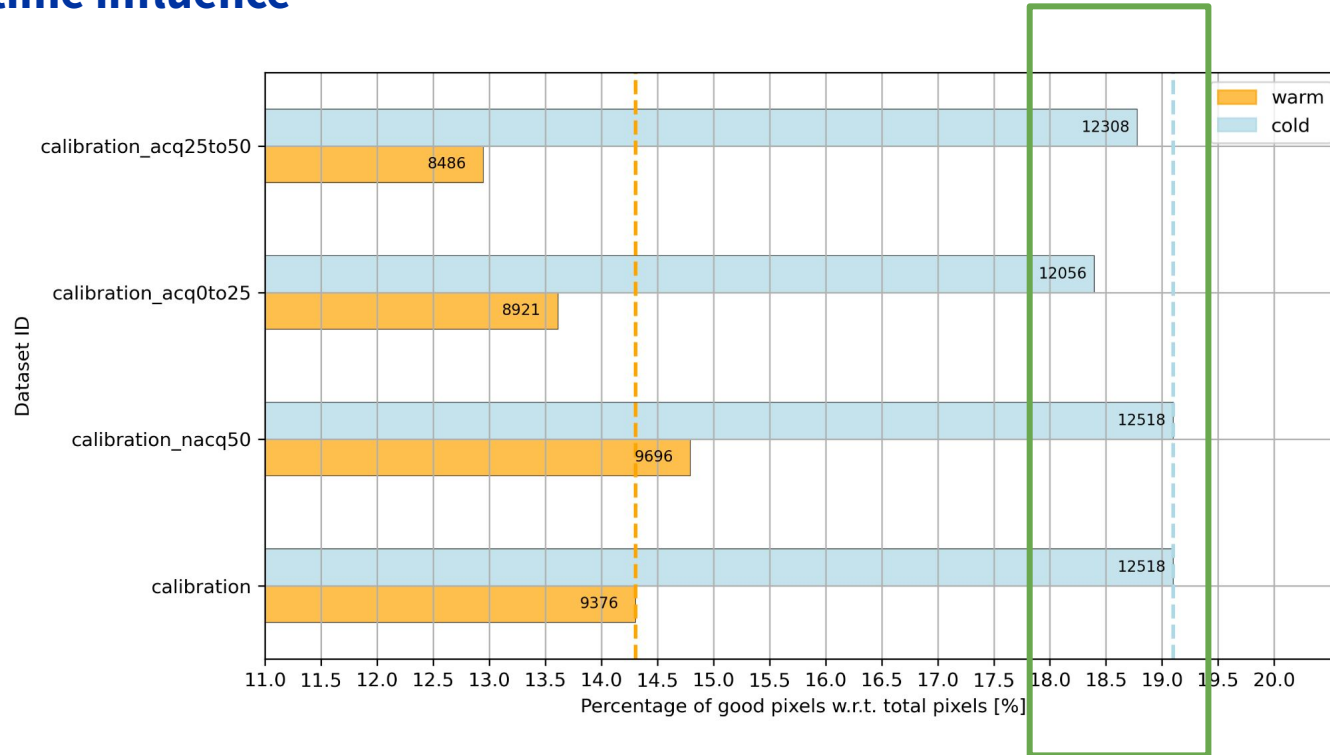
Systematic uncertainties and biases

Exposure time influence



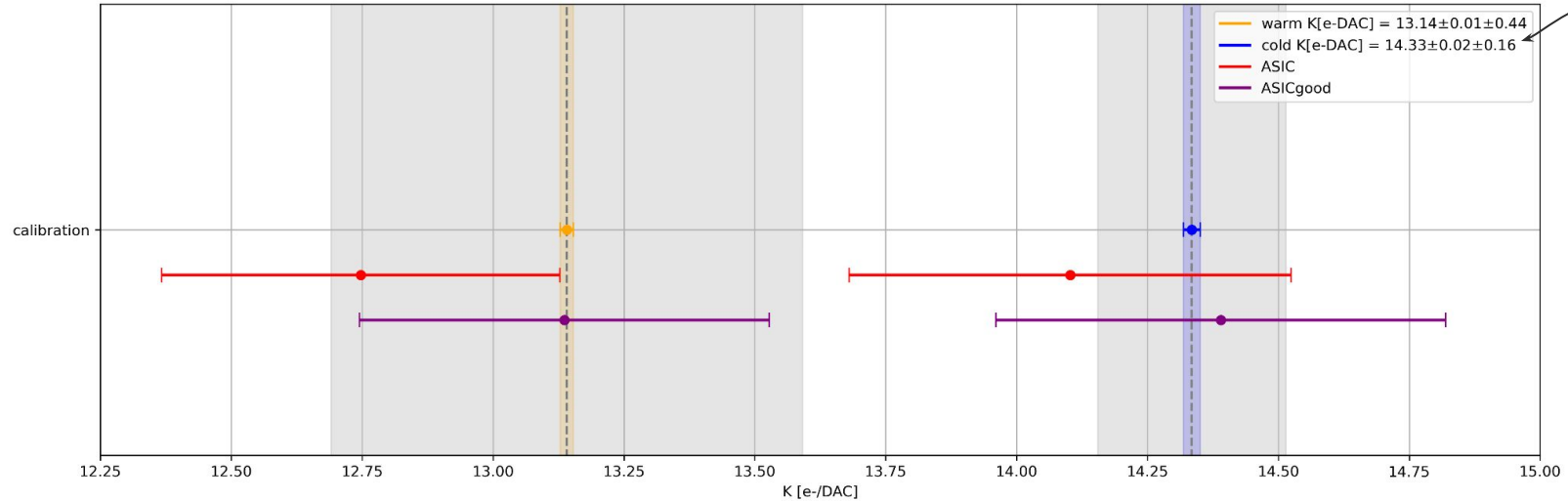
Systematic uncertainties and biases

Exposure time influence



Systematic uncertainties and biases

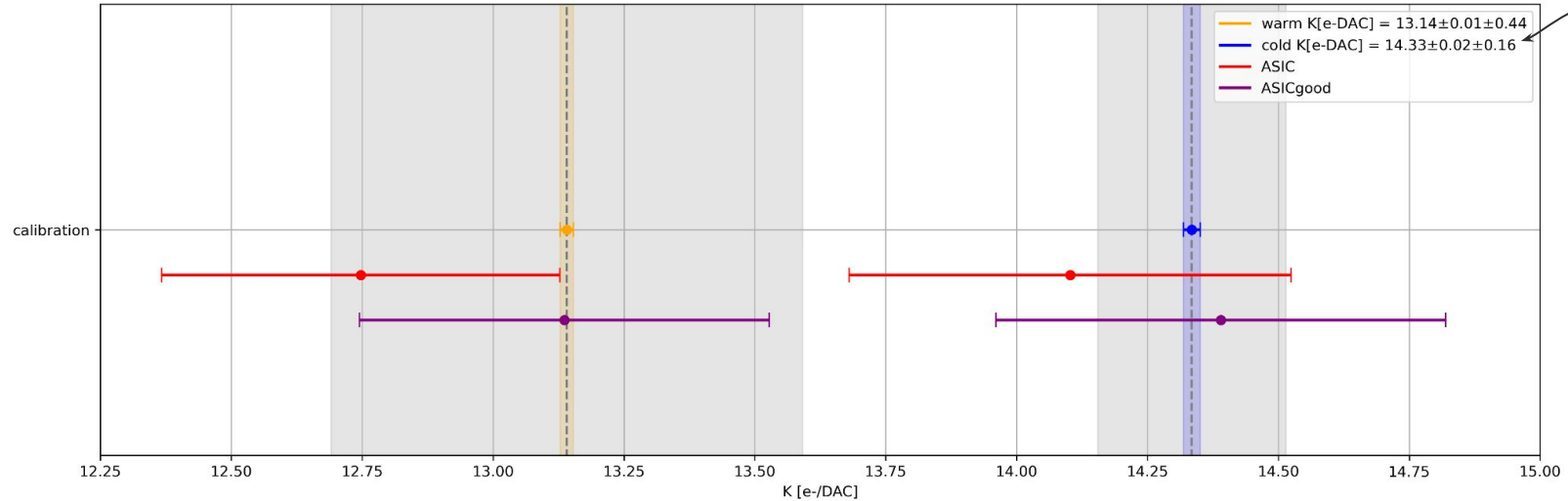
Exposure time influence



Assign a systematic uncertainty to the gain $K[e\text{-DAC}]$

Systematic uncertainties and biases

Exposure time influence



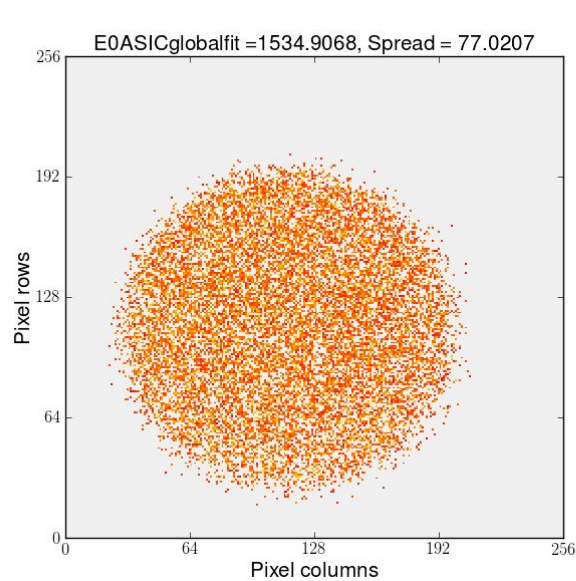
Assign a systematic uncertainty to the gain $K[e\text{-DAC}]$

ASIC Gain makes a *good* prediction of Mean Gain

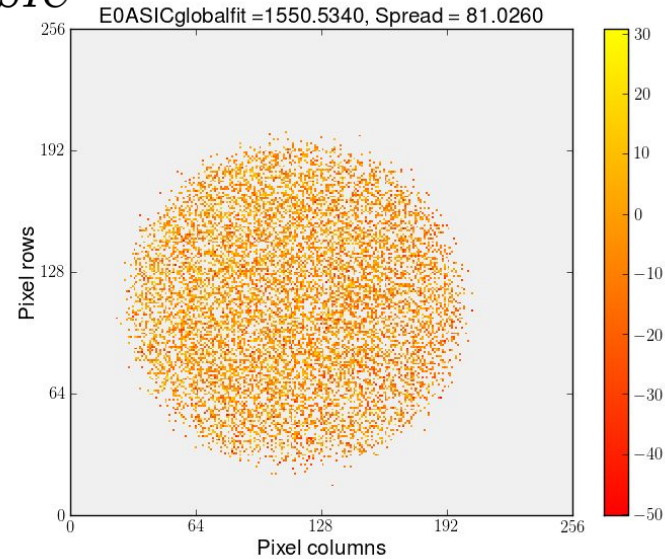
Systematic uncertainties and biases

Pixel coordinate bias

Cold



$E_0 - E_{0ASIC}$



Warm

No correlation of pixel coordinate and value of E_0

Systematic uncertainties and biases

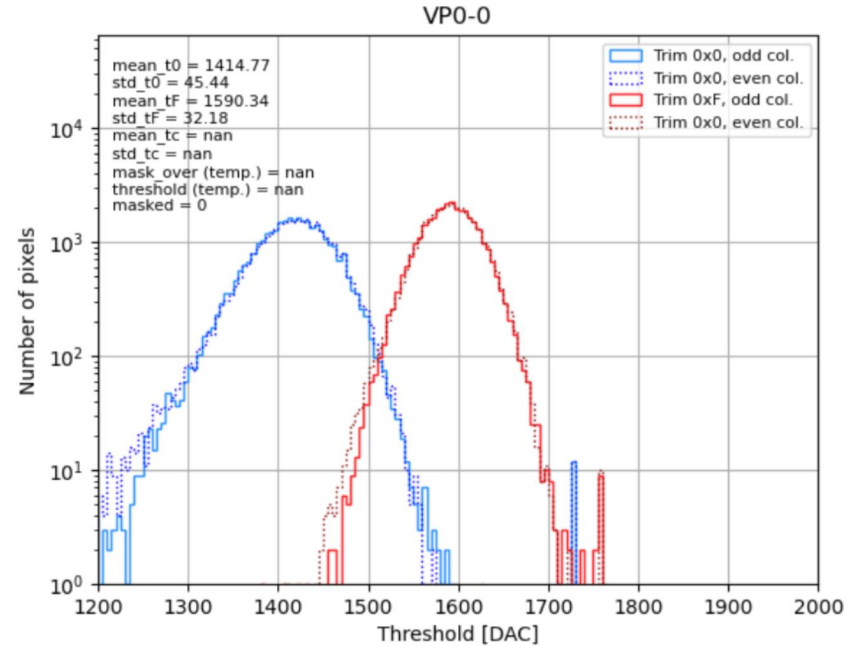
Pixel coordinate bias

Pattern observed in equalisation

Groups: *even* and *odd* columns + 16ths rows

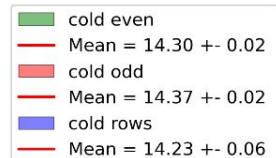
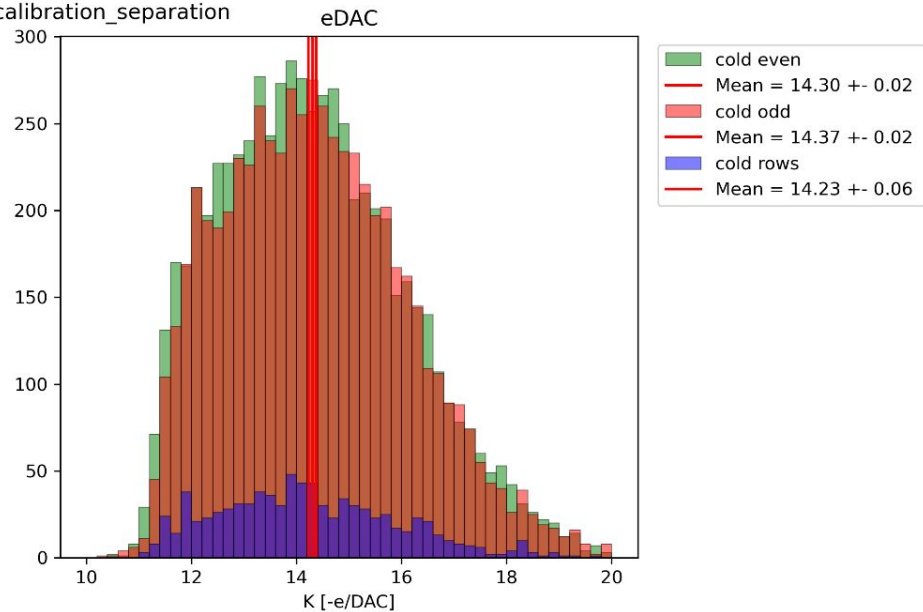
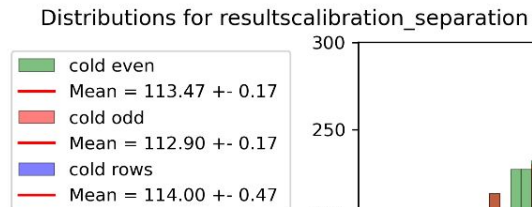
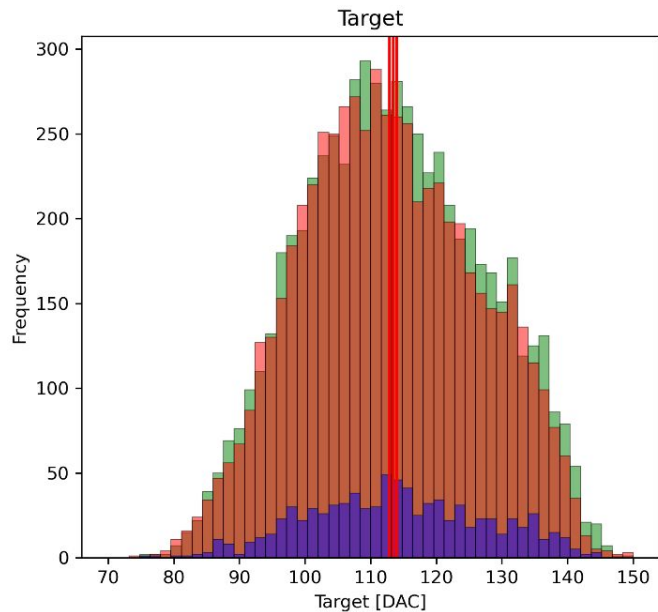
Based on equalisation approach:

1. Same 3 groups
2. Analyse each group with same procedure



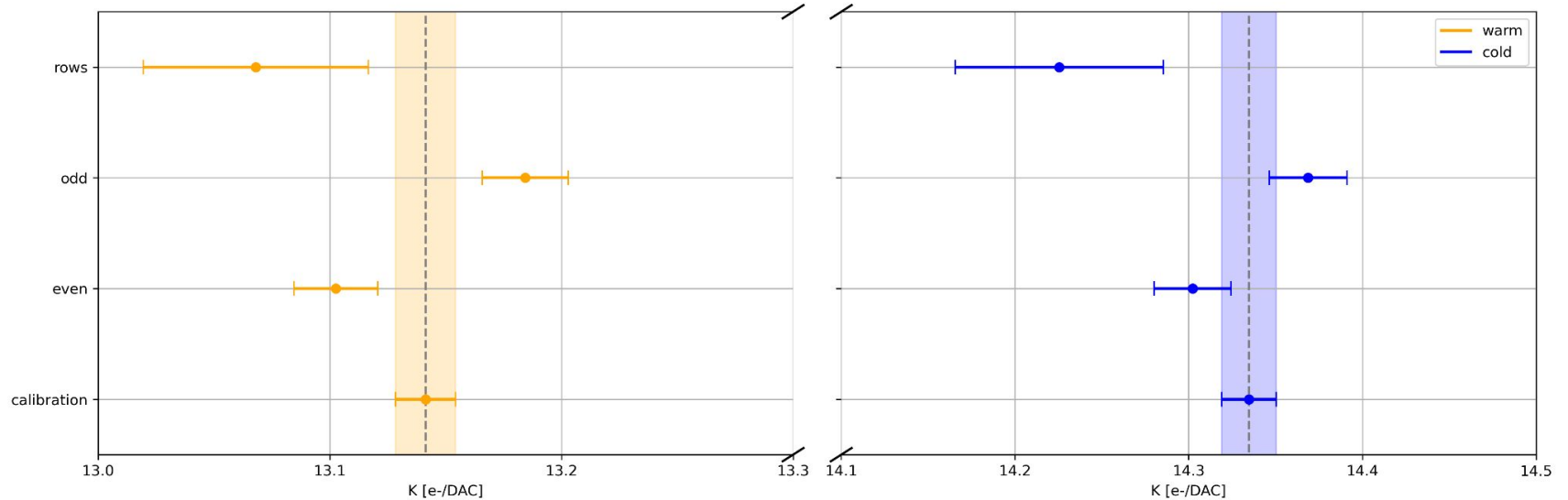
Systematic uncertainties and biases

Pixel coordinate bias



Systematic uncertainties and biases

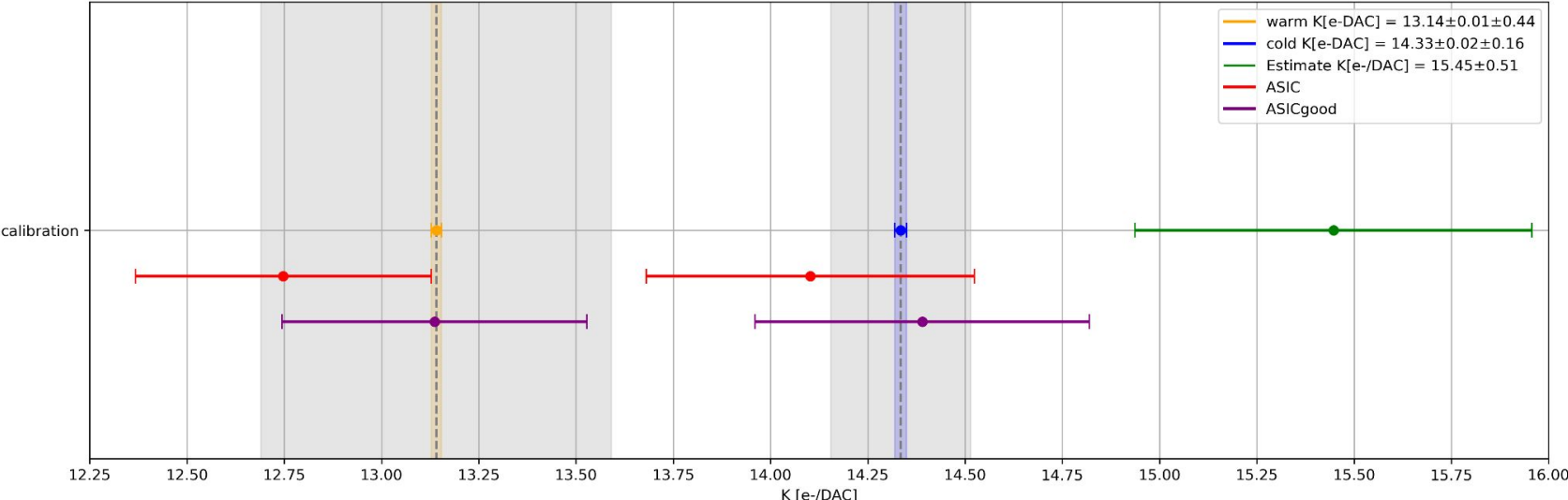
Pixel coordinate bias



Disagreement on mean gain among groups. Bias coming from pixel position.

Conclusions

K [e-/DAC] obtained for two datasets with Fe55 irradiation:

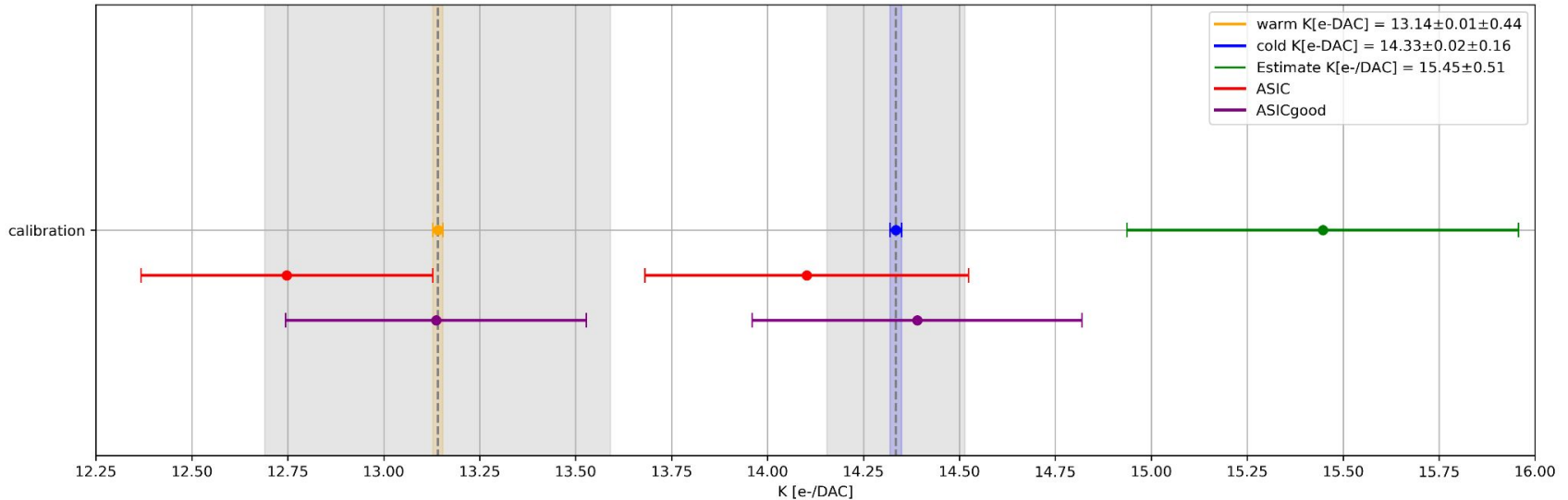


Estimate and cold Mean differ by 2.07σ

Mean Gain found is still somewhat *compatible* with Paper Estimate

Conclusions

K [e-/DAC] obtained for two datasets with Fe55 irradiation:



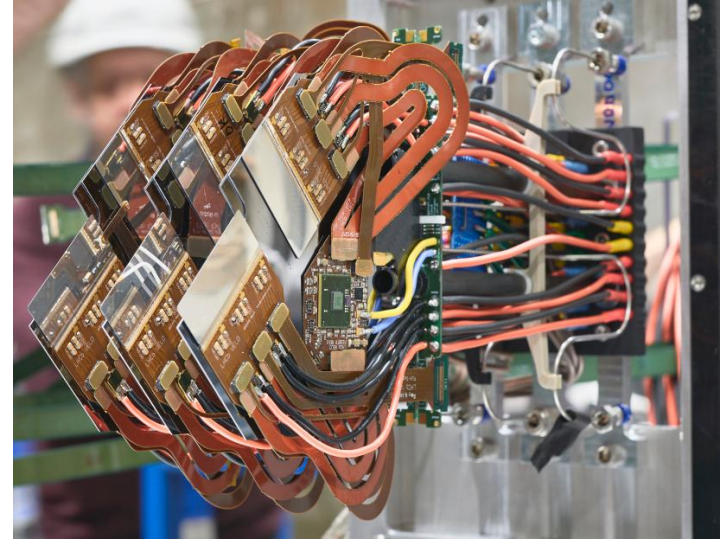
Maybe lower temperatures \Rightarrow Mean gain from data approaches Estimate Gain?

Label	Module Temp.	ASIC	Total time(h)	Gain K_{mean} [e-/DAC]
Cold	-20°C	VP3-1	4.36	$14.33 \pm 0.02 \pm 0.16$
Warm	20°C	VP3-1	8.73	$13.14 \pm 0.01 \pm 0.44$

Conclusions

Summary:

- Method to obtain Gain from irradiation of ASICs
- ASIC flux is not bad predictor for Mean Gain
- Positional bias observed

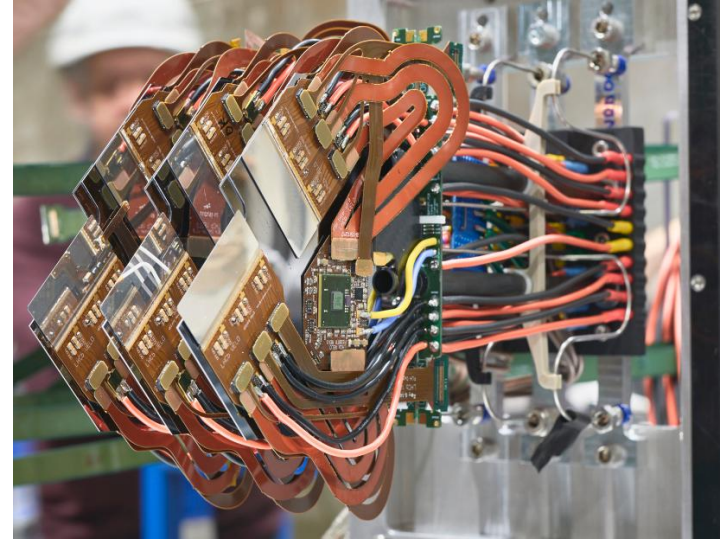


Label	Module Temp.	ASIC	Total time(h)	Gain K_{mean} [e-/DAC]
Cold	-20°C	VP3-1	4.36	$14.33 \pm 0.02 \pm 0.16$
Warm	20°C	VP3-1	8.73	$13.14 \pm 0.01 \pm 0.44$

Conclusions

Future:

- Repeat analysis with new data and new equalisation running on MiniDAQ3
- Better determination of sys. uncertainty
- Repeat on other ASICs and temperatures



Label	Module Temp.	ASIC	Total time(h)	Gain K_{mean} [e-/DAC]
Cold	-20°C	VP3-1	4.36	$14.33 \pm 0.02 \pm 0.16$
Warm	20°C	VP3-1	8.73	$13.14 \pm 0.01 \pm 0.44$

Thank you for your attention.

Questions or suggestions?

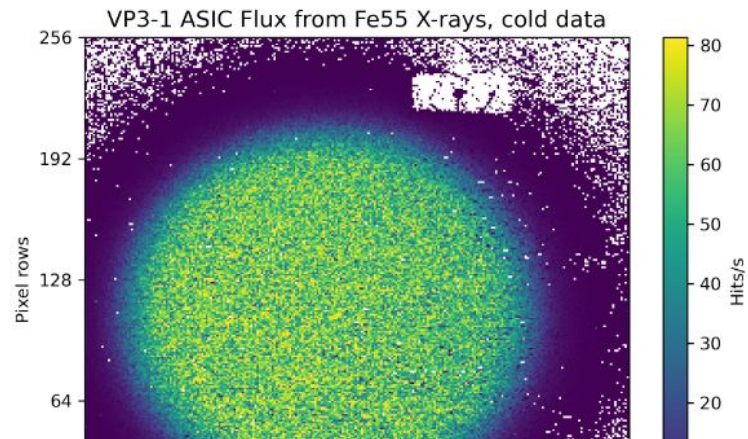
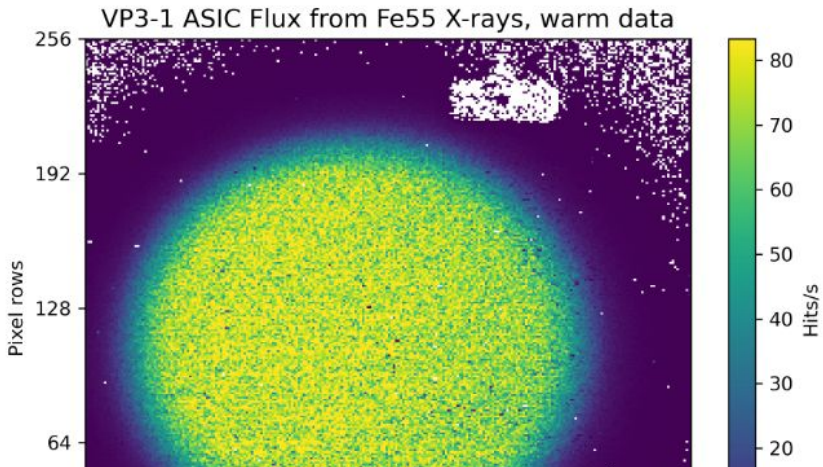
Extra slides

Vertex Locator (VELO)

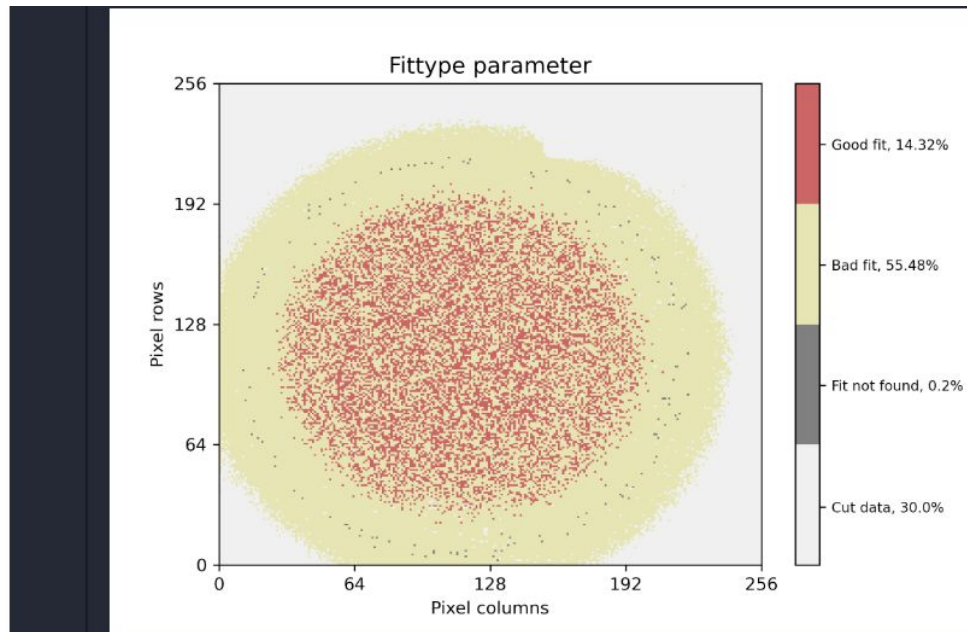
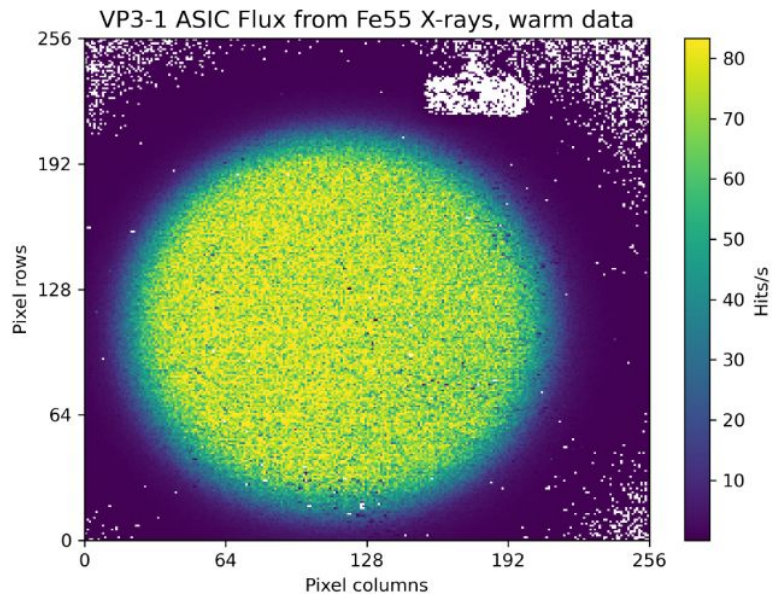
Table 1. Specifications of the upgraded VELO compared to those of the original version.

	2009–2018	2022
RF box inner radius (minimum thickness)	5.5 mm (300 μm)	3.5 mm (150 μm)
Inner radius of active silicon detector	8.2 mm	5.1 mm
Total fluence (silicon tip) [$n_{\text{eq}}/\text{cm}^2$]	4×10^{14}	$\sim 8 \times 10^{15}$
Sensor segmentation	$r - \phi$ strips	square pixels
Total active area of Si detectors	0.22 m^2	0.12 m^2
Pitch (strip or pixel)	37–97 μm	55 μm
Technology	n-on-n	n-on-p
Number of modules	42	52
Total number of channels	172 thousand	41 million
Readout rate [MHz]	1, analogue	40, zero suppressed
Whole-VELO data rate	150 Gbit/s	~ 2 Tbit/s
Total power dissipation (in vacuum)	800 W	~ 2 kW

Vertex Locator (VELO)

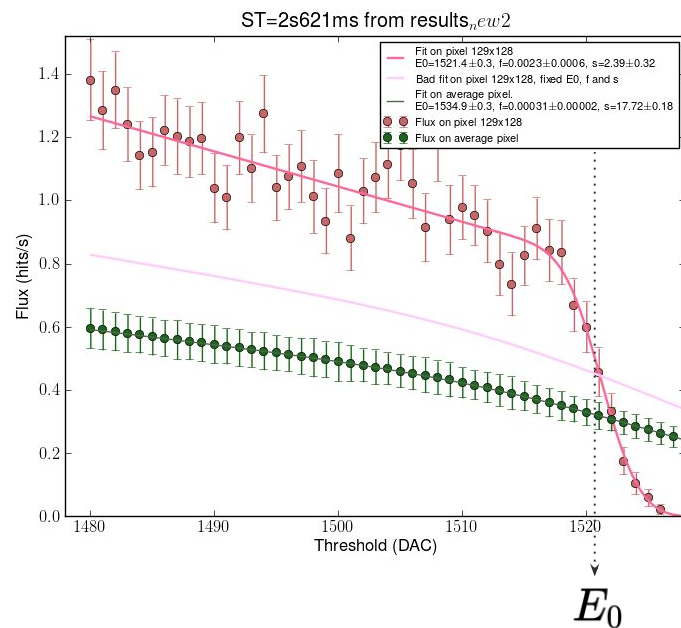
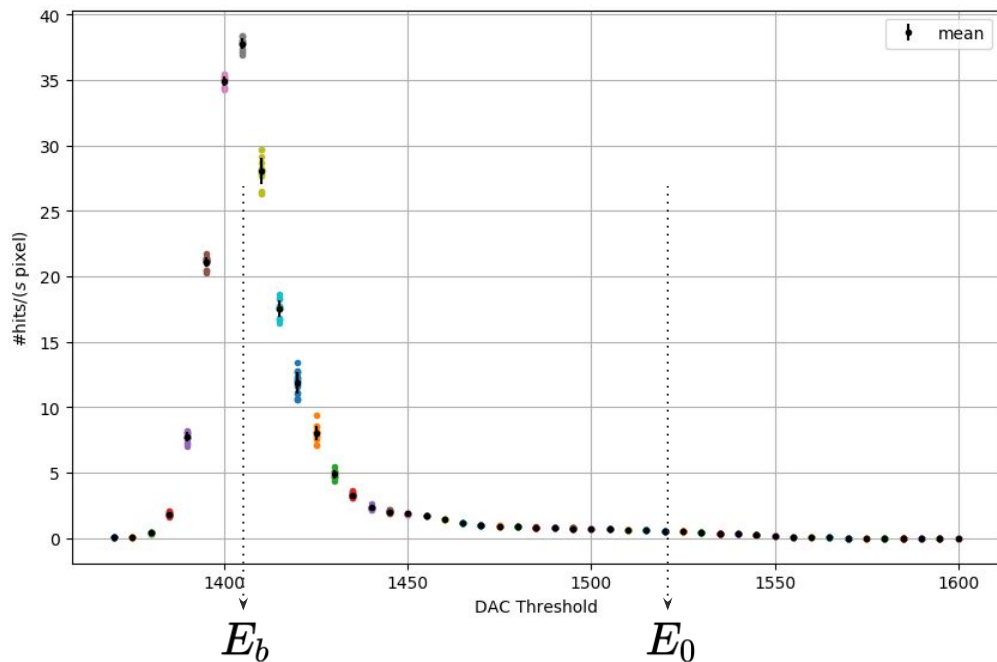


Vertex Locator (VELO)

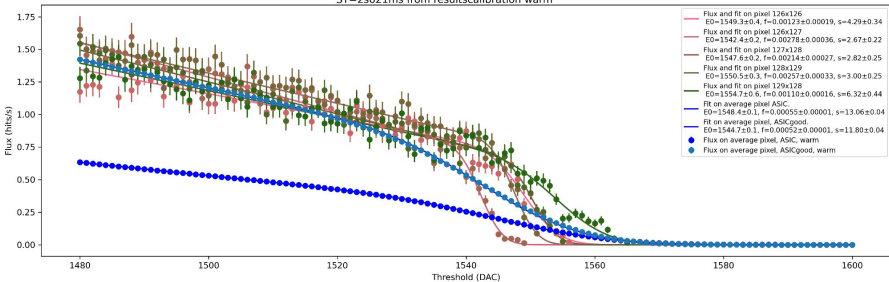


Flux over thr

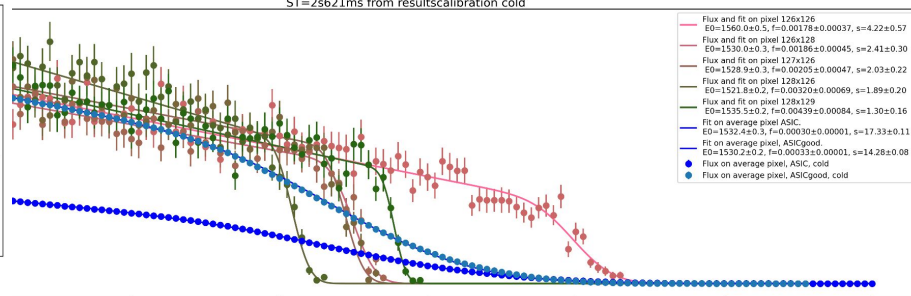
Flux vs Thr [DAC]



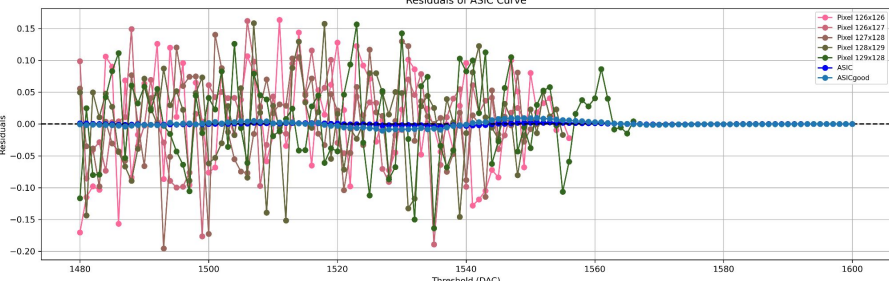
ST=2s621ms from resultscalibration warm



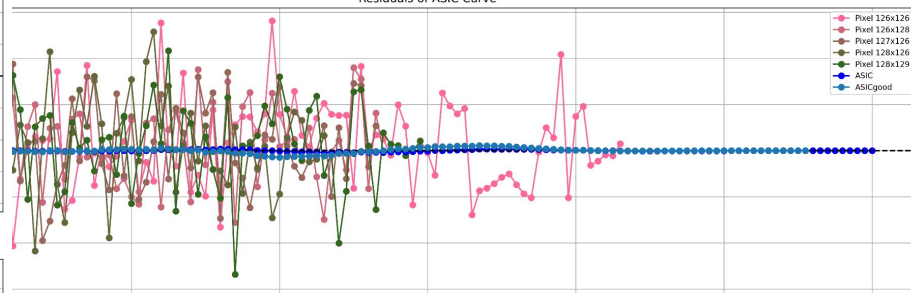
ST=2s621ms from resultscalibration cold



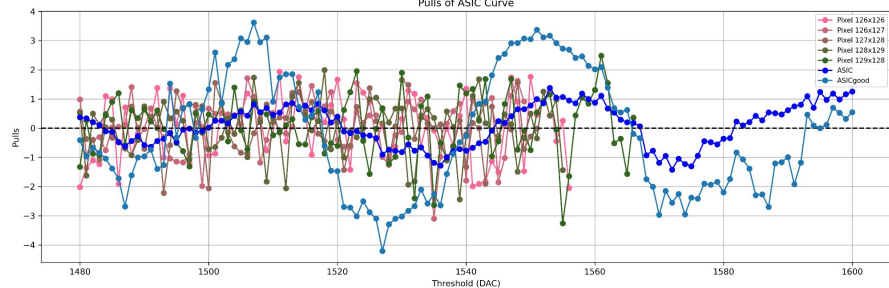
Residuals of ASIC Curve



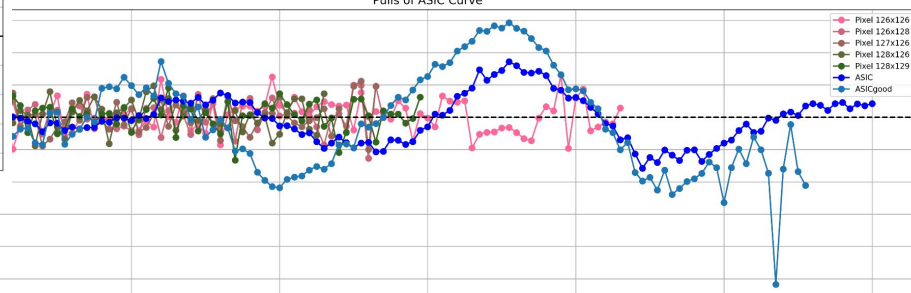
Residuals of ASIC Curve



Pulls of ASIC Curve



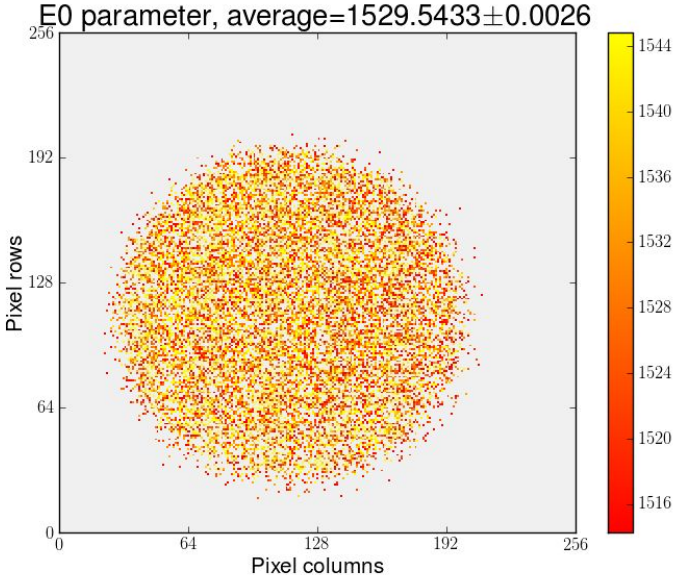
Pulls of ASIC Curve



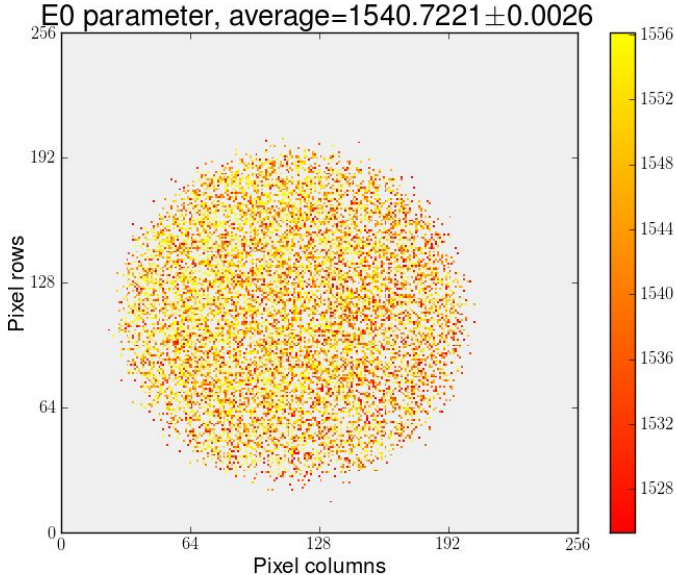
E0 Analysis

Heatmap of E0

Cold



Warm



Analysis: Target

Calculation of $target = E_0 - E_b \rightarrow$ need E_b

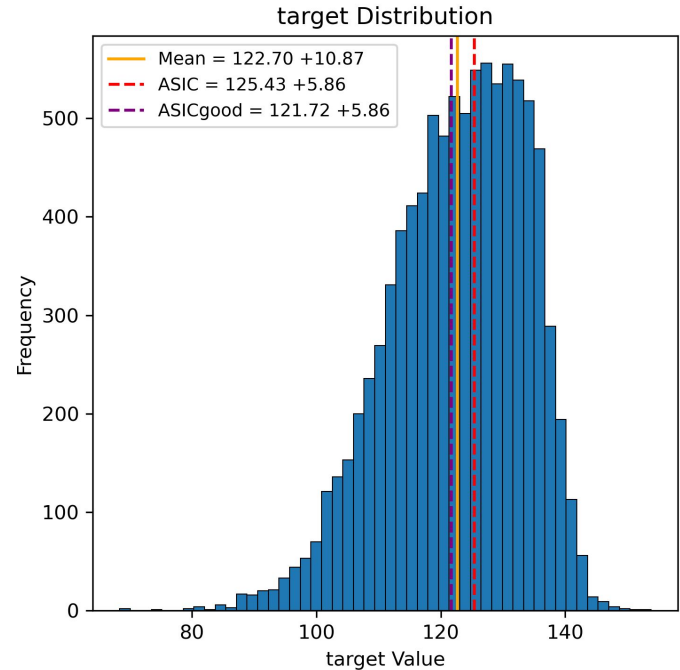
Individual pixel values

- E_b using the best prediction from equalisation
- ΔE_b noise width of either Trim0 or TrimF

ASIC

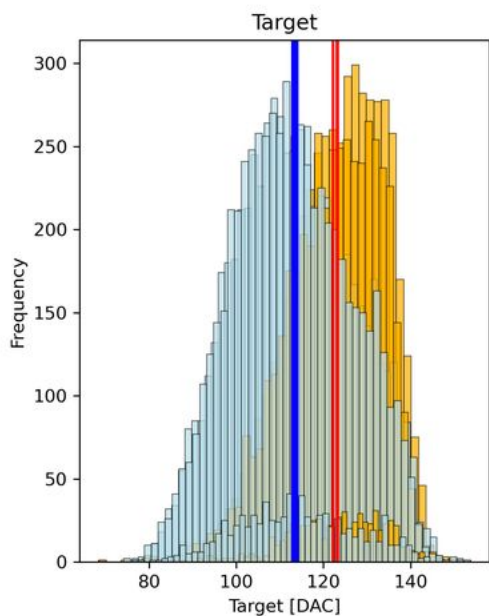
$$target_{ASIC} = E_{0ASIC} - mean(E_b)$$
$$\Delta target_{ASIC} = \sqrt{(\Delta E_{0ASIC})^2 + (\Delta E_{bASIC})^2}$$

ASICgood (same as ASIC)



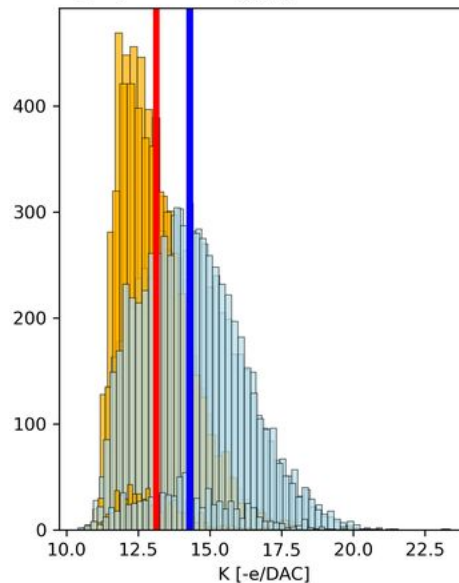
Separation: even, odd, 16th rows

Means



- warm even, skewness: -0.55, kurtosis: 0.08
- Mean = 123.09 +- 11.05
- cold even, skewness: 0.07, kurtosis: -0.66
- Mean = 113.47 +- 13.71
- warm odd, skewness: -0.57, kurtosis: 0.16
- Mean = 122.21 +- 10.71
- cold odd, skewness: 0.08, kurtosis: -0.61
- Mean = 112.90 +- 13.44
- warm rows, skewness: -0.52, kurtosis: 0.08
- Mean = 123.32 +- 10.58
- cold rows, skewness: 0.02, kurtosis: -0.58
- Mean = 114.00 +- 13.41

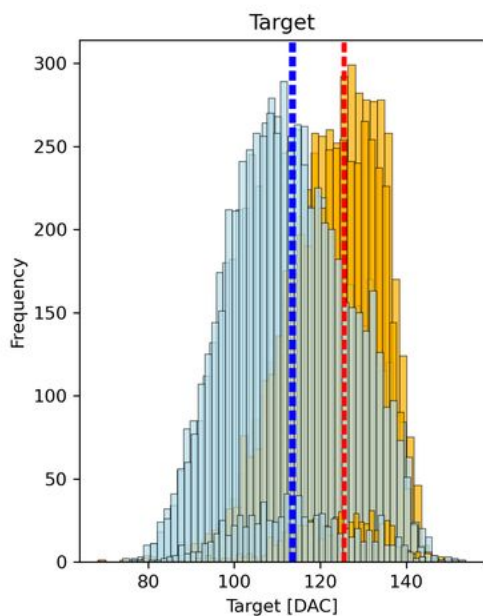
Distributions for resultscheck_separation eDAC



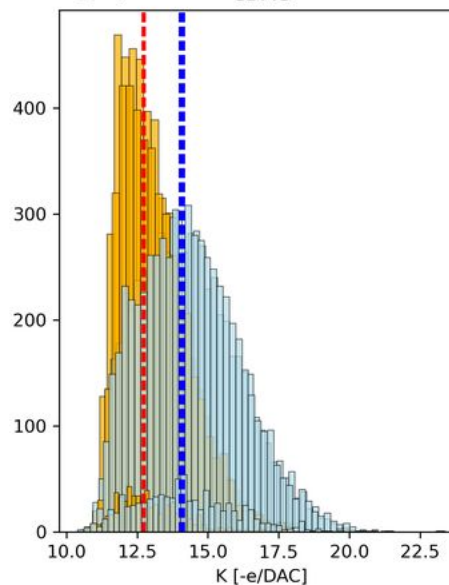
- warm even, skewness: 1.17, kurtosis: 2.36
- Mean = 13.10 +- 1.27
- cold even, skewness: 0.45, kurtosis: -0.24
- Mean = 14.30 +- 1.77
- warm odd, skewness: 1.23, kurtosis: 2.98
- Mean = 13.19 +- 1.25
- cold odd, skewness: 0.46, kurtosis: -0.14
- Mean = 14.37 +- 1.75
- warm rows, skewness: 1.09, kurtosis: 1.81
- Mean = 13.07 +- 1.20
- cold rows, skewness: 0.54, kurtosis: 0.09
- Mean = 14.23 +- 1.72

Separation: even, odd, 16th rows

ASIC

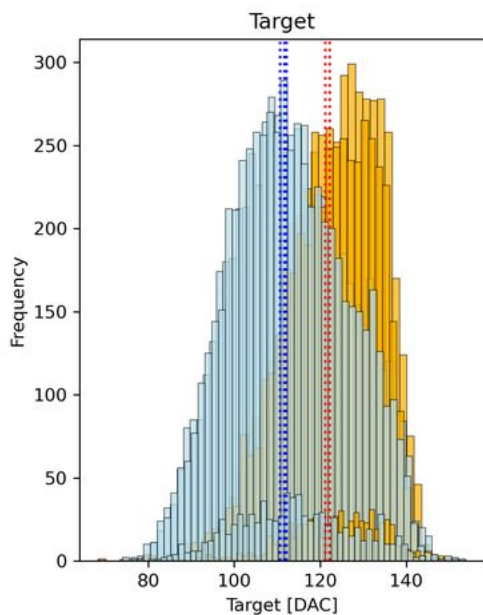


Distributions for resultcheck_separation eDAC

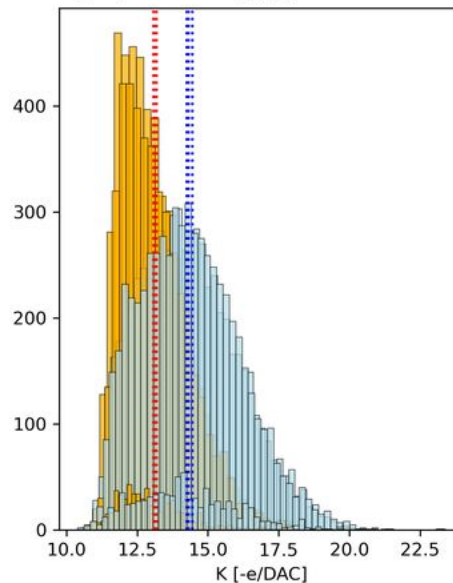


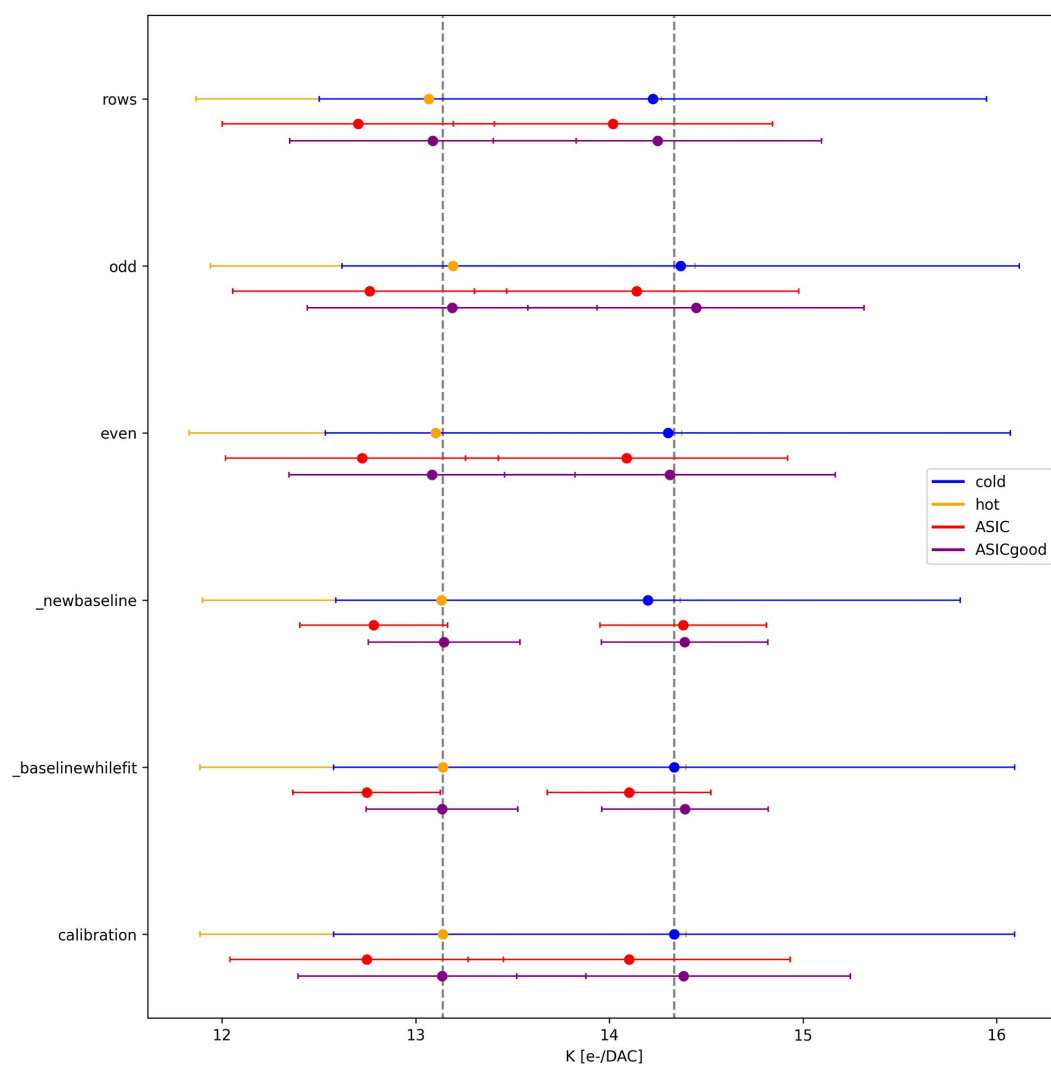
Separation: even, odd, 16th rows

ASICgood



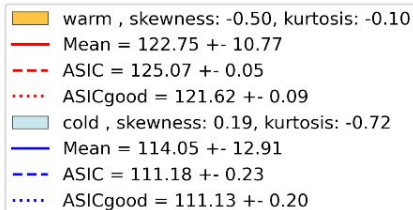
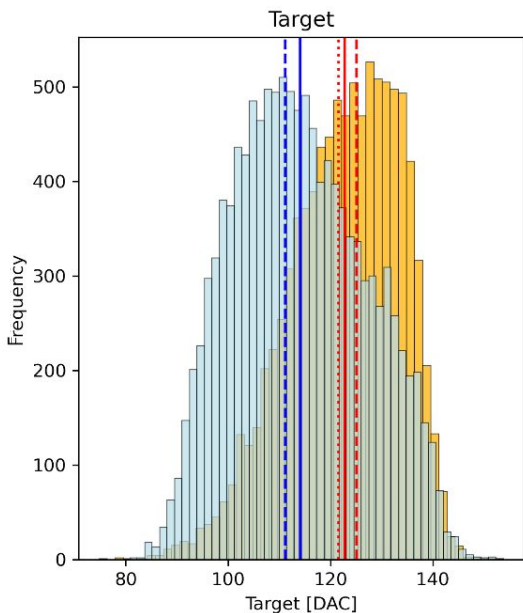
Distributions for resultcheck_separation eDAC



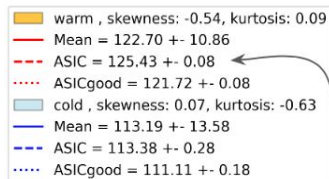


Baseline inclusion approaches

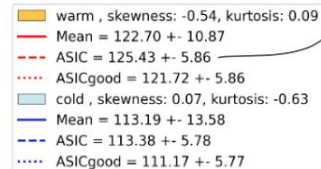
_newbaseline: shift in generation of flux files.



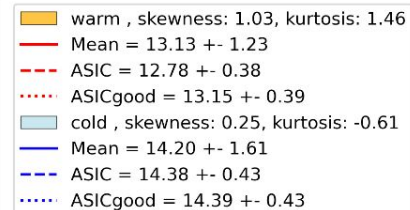
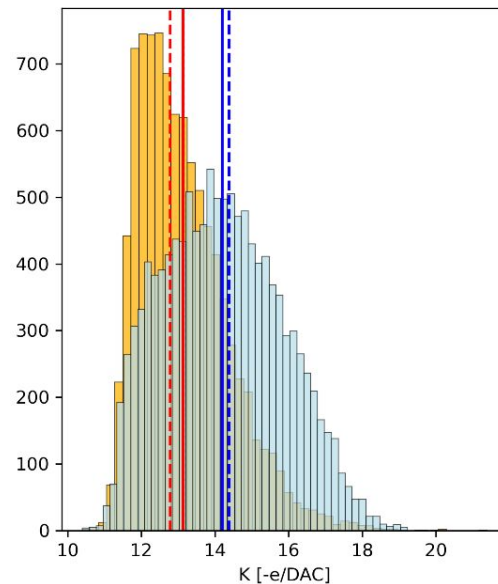
_baseline



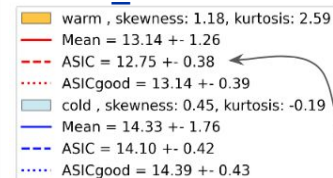
calibration



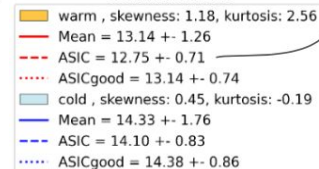
Distributions for resultsultimate_newbaseline eDAC



_baseline

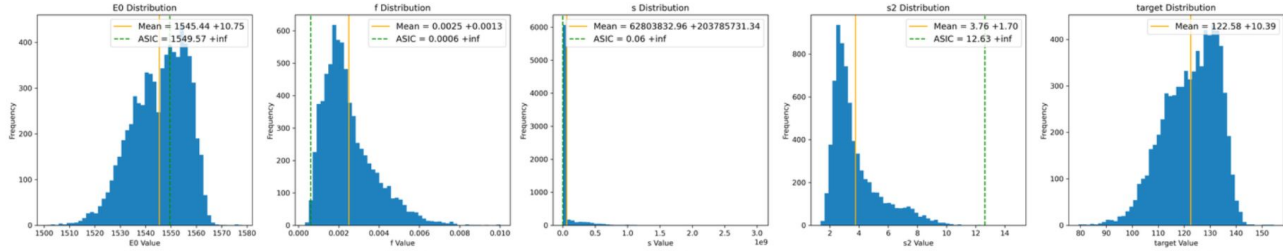


calibration

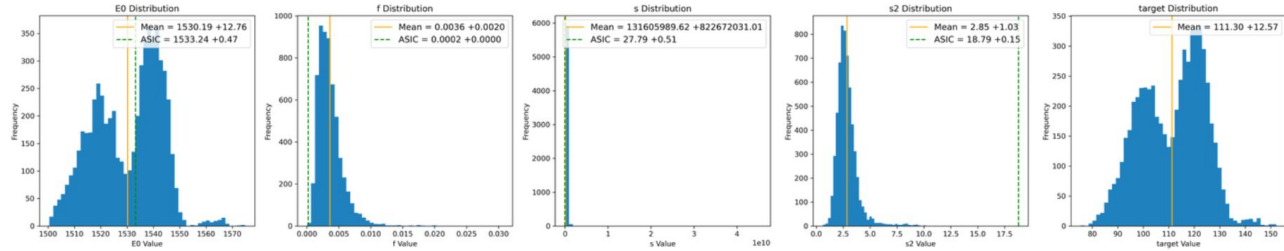


Double s parameter in Flux equation

cold



warm



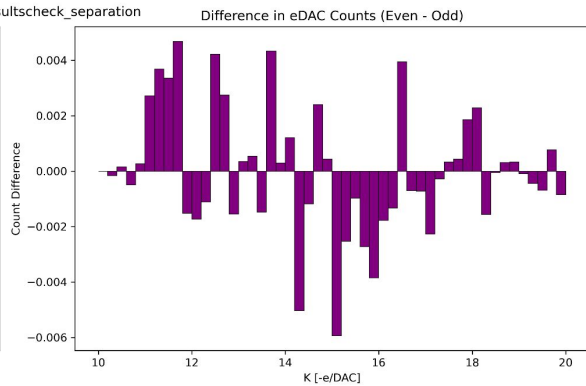
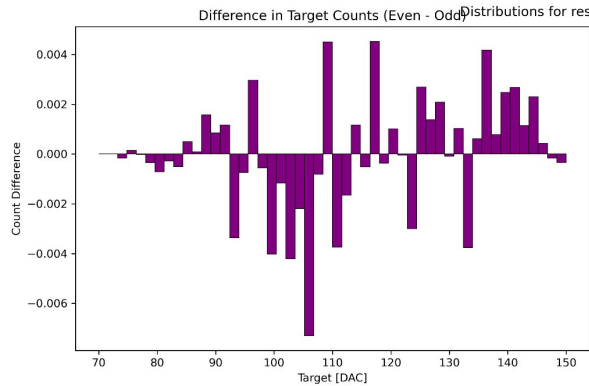
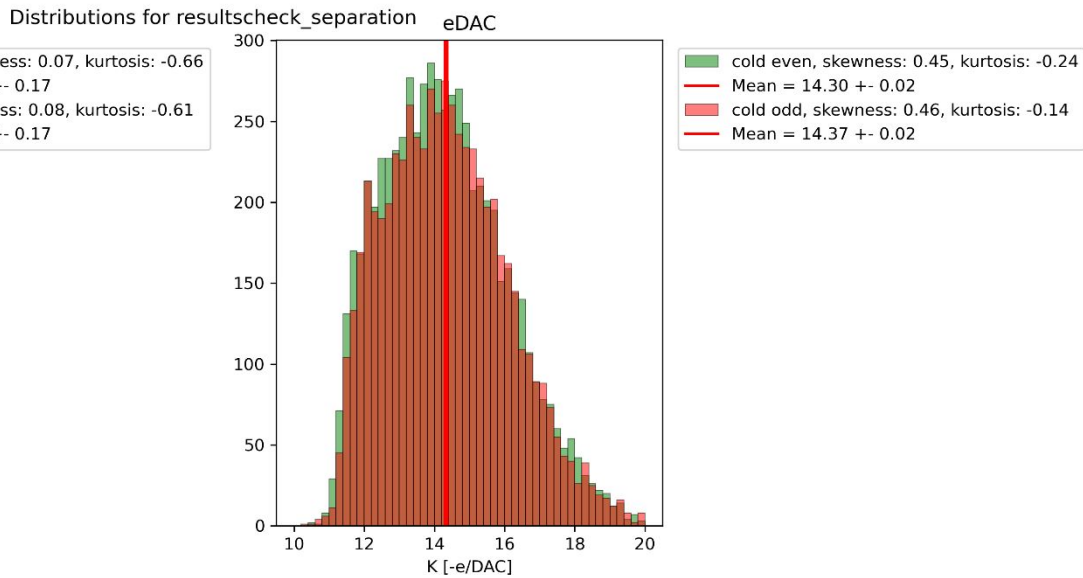
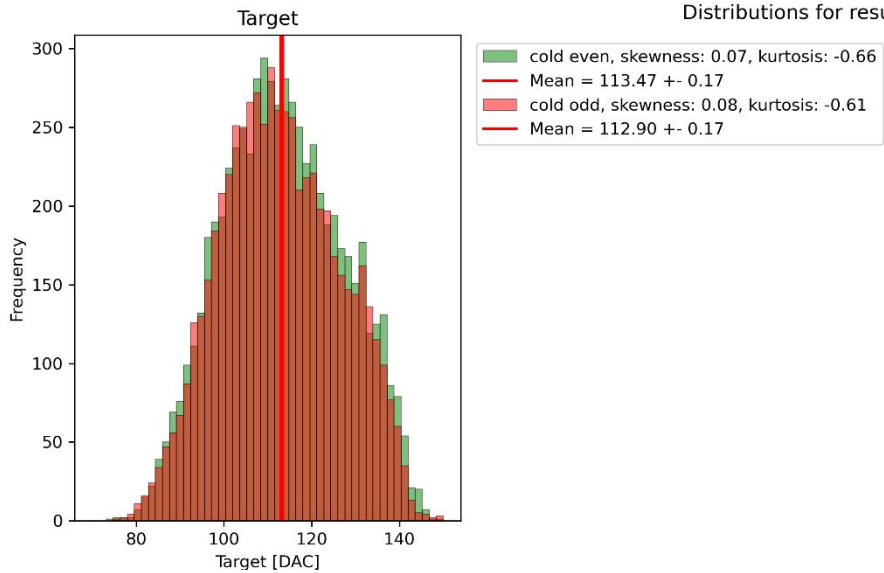
$$F(E) = Af \cdot \frac{1}{2} \left(\left(\frac{s}{\sqrt{2}} \right)^2 + (E0 - E) \cdot \operatorname{erfc} \left(\frac{E - E0}{s} \right) \right) + A(1 - f) \cdot \frac{1}{s_2 \sqrt{8\pi}} \cdot \operatorname{erfc} \left(\frac{E - E0}{s_2 \sqrt{2}} \right)$$

```
KASIC = n_ehp/targetASIC
```

```
uKASIC = KASIC*np.sqrt((n_ehp_err/n_ehp)**2 + (utargetASIC/targetASIC)**2)
```

```
KASICgood =n_ehp/targetASICgood
```

```
uKASICgood = KASICgood*np.sqrt((n_ehp_err/n_ehp)**2 + (utargetASICgood/targetASICgood)**2)
```



Approaches on baseline inclusion

Shifting E0 by baseline before or after fit should lead to the same target result.

Calibration: shift after fitting. Get E0, then →

$$target = E_0 - E_b$$

$$target_{ASIC} = E_{0ASIC} - mean(E_b)$$

baselinewhilefit: shift while fitting. Get *target* directly from fit, also for ASIC

_newbaseline: shift in generation flux files

$$\Delta target_{ASIC} = \sqrt{\Delta E_{0ASIC}^2 + (\Delta E_b)^2}$$

$$target_{ASIC} = E_{0ASIC} - mean(E_b)$$

$$\Delta target_{ASIC} = \sqrt{(\Delta E_{0ASIC})^2 + (\Delta E_b)^2}$$

Approaches on baseline inclusion

baselinewhilefit approach

$$\text{hits}_{ASIC;thr} = \sum_{i,j} \text{hits}_{i,j;thr} = 5 \cdot 10^4 \quad \text{hits}_{ASIC;thr} = 6.3 \cdot 10^4$$

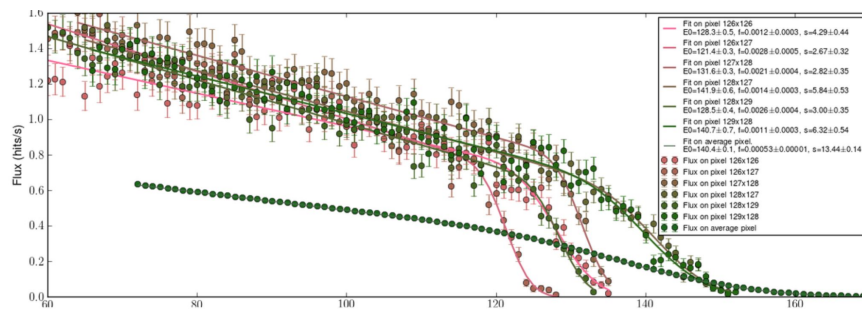
$$\text{hits}_{thr} = \begin{bmatrix} 0 & 4 & 16 & \dots & 2 & 0 \\ 1 & 7 & 43 & \dots & 5 & 1 \\ \vdots & \vdots & \vdots & \ddots & \vdots & \vdots \\ 0 & 2 & 1 & \dots & 0 & 0 \end{bmatrix} \quad \text{hits}_{thr} = \begin{bmatrix} 0 & 6 & 8 & \dots & 0 & 0 \\ 2 & 9 & 21 & \dots & 0 & 0 \\ \vdots & \vdots & \vdots & \ddots & \vdots & \vdots \\ 0 & 0 & 0 & \dots & 1 & 0 \end{bmatrix}$$

not all pixels mapped to same newthr

$$\text{hits}_{newthr} = \begin{bmatrix} 0 & 0 & 16 & \dots & 0 & 0 \\ 0 & 0 & 0 & \dots & 0 & 0 \\ \vdots & \vdots & \vdots & \ddots & \vdots & \vdots \\ 0 & 2 & 0 & \dots & 0 & 0 \end{bmatrix}$$

$$\text{hits}_{ASIC;newthr_{ASIC}} = 5 \cdot 10^4 \quad \text{hits}_{ASIC;newthr_{ASIC}} = 6.3 \cdot 10^4$$

hitsASIC directly shifted with baseline_ASIC



$$\text{newthr}_{i,j} = \text{thr} - \text{baseline}_{i,j}$$

$$\text{baseline}_{ASIC} = \overline{\text{baseline}} \approx 1420 \text{ [DAC]}$$

$$\text{baseline} = \begin{bmatrix} 1425 & 1417 & 1438 & \dots & 1422 & 1419 \\ 1420 & 1424 & 1419 & \dots & 1428 & 1427 \\ \vdots & \vdots & \vdots & \ddots & \vdots & \vdots \\ 1416 & 1438 & 1418 & \dots & 1421 & 1413 \end{bmatrix}$$

old baseline method
shift introduced in fitting and use of baseline_ASIC

Approaches on baseline inclusion

_newbaseline approach

$$\text{hits}_{ASIC;thr} = \sum_{i,j} \text{hits}_{i,j;thr} = 5 \cdot 10^4 \quad \text{hits}_{ASIC;thr} = 6.3 \cdot 10^4$$

$$\text{hits}_{thr} = \begin{bmatrix} 0 & 4 & 16 & \dots & 2 & 0 \\ 1 & 7 & 43 & \dots & 5 & 1 \\ \vdots & \vdots & \vdots & \ddots & \vdots & \vdots \\ 0 & 2 & 1 & \dots & 0 & 0 \end{bmatrix} \quad \text{hits}_{thr} = \begin{bmatrix} 0 & 6 & 8 & \dots & 0 & 0 \\ 2 & 9 & 21 & \dots & 0 & 0 \\ \vdots & \vdots & \vdots & \ddots & \vdots & \vdots \\ 0 & 0 & 0 & \dots & 1 & 0 \end{bmatrix}$$

1480

1500

1600 [DAC]

≠

not all pixels mapped to same newthr

$$\text{hits}_{newthr} = \begin{bmatrix} 0 & 0 & 16 & \dots & 0 & 0 \\ 0 & 0 & 0 & \dots & 0 & 0 \\ \vdots & \vdots & \vdots & \ddots & \vdots & \vdots \\ 0 & 2 & 0 & \dots & 0 & 0 \end{bmatrix}$$

42

60

80

198 [DAC]

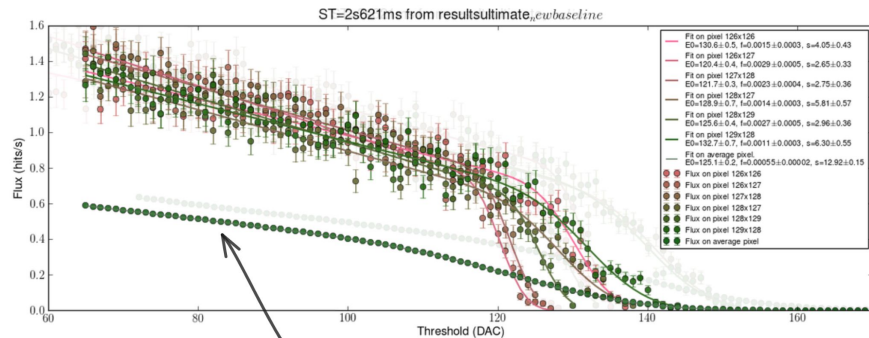
$$\text{hits}_{ASIC;newthr} = \sum_{i,j} \text{hits}_{i,j;newthr} = 2.8 \cdot 10^3$$

hitsASIC directly from hits_newthr,
no shift with baseline_ASIC needed

$$\text{newthr}_{i,j} = \text{thr} - \text{baseline}_{i,j}$$

baseline =

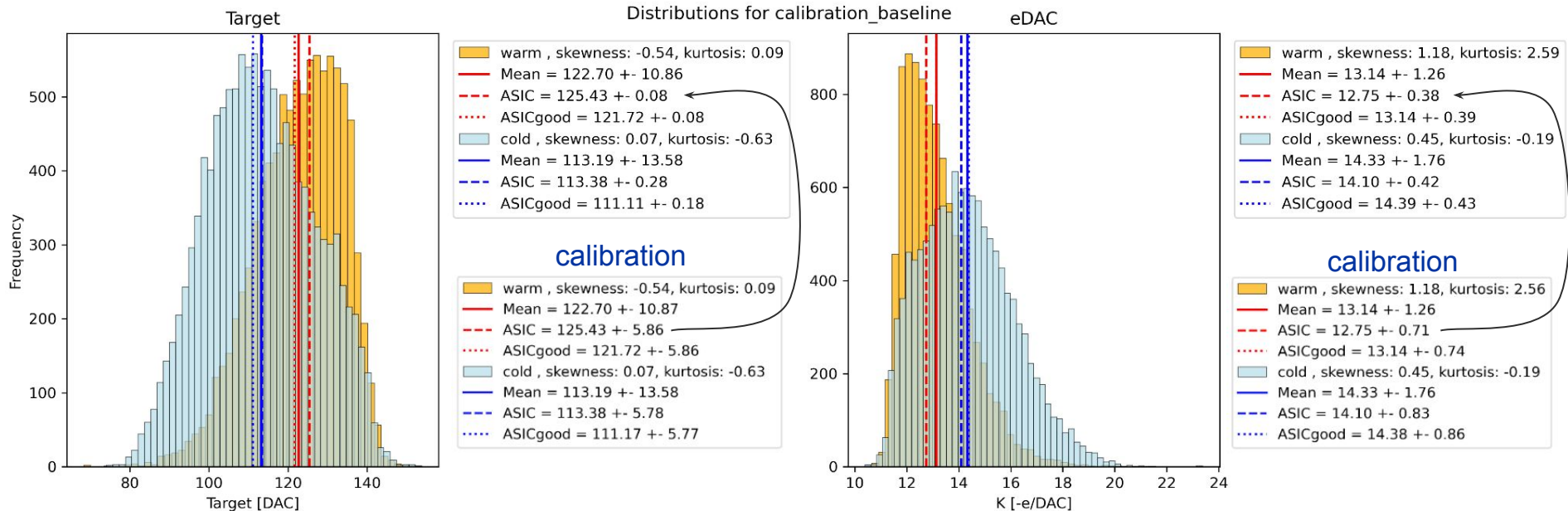
$$\begin{bmatrix} 1425 & 1417 & 1438 & \dots & 1422 & 1419 \\ 1420 & 1424 & 1419 & \dots & 1428 & 1427 \\ \vdots & \vdots & \vdots & \ddots & \vdots & \vdots \\ 1416 & 1438 & 1418 & \dots & 1421 & 1413 \end{bmatrix}$$



new baseline method
shift introduced in flux files generation and no use of baselineASIC

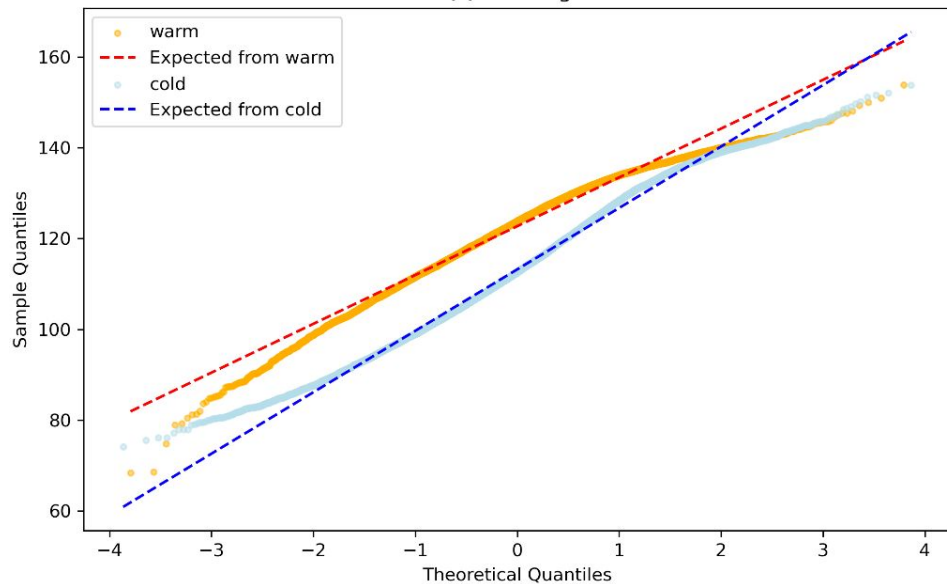
Approaches on baseline inclusion

baselinewhilefit: shift while fitting. Get *target* directly from fit, also for ASIC

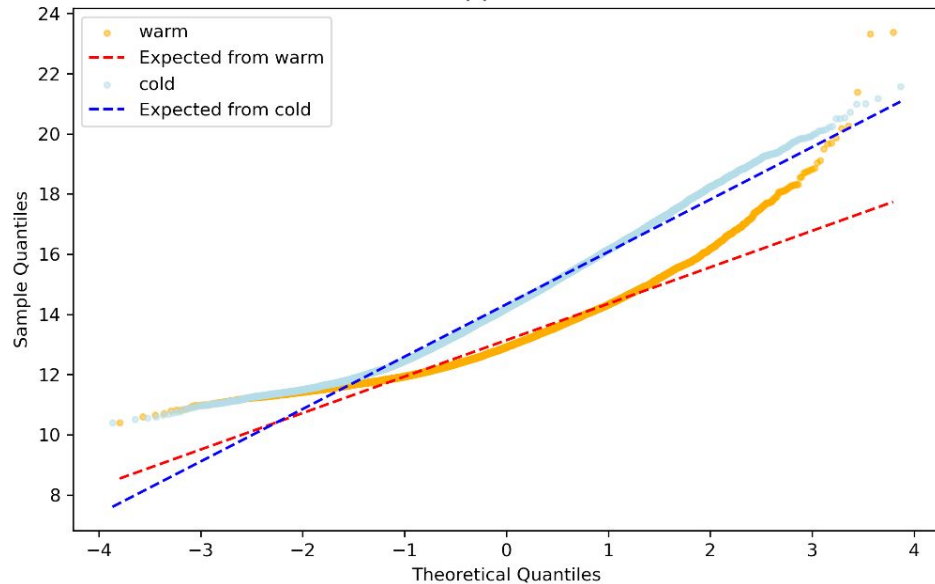


How Gaussian is the data?

QQ Plot target



QQ Plot K



Conclusions

K [e-/DAC] obtained for two datasets of Fe55:

Comparing (cold) ASIC and ASICgood to :

- Mean Gain

```
Comparing cold dataset to KASIC ...  
Distance in standard deviations from KASIC: -0.51  
Comparing cold dataset to KASICgood ...  
Distance in standard deviations from KASICgood: 0.12
```

- Estimate Gain

```
Comparing cold to KASIC ...  
Distance in standard deviations from KASIC: -1.97  
Comparing cold to KASICgood ...  
Distance in standard deviations from KASICgood: -1.54
```